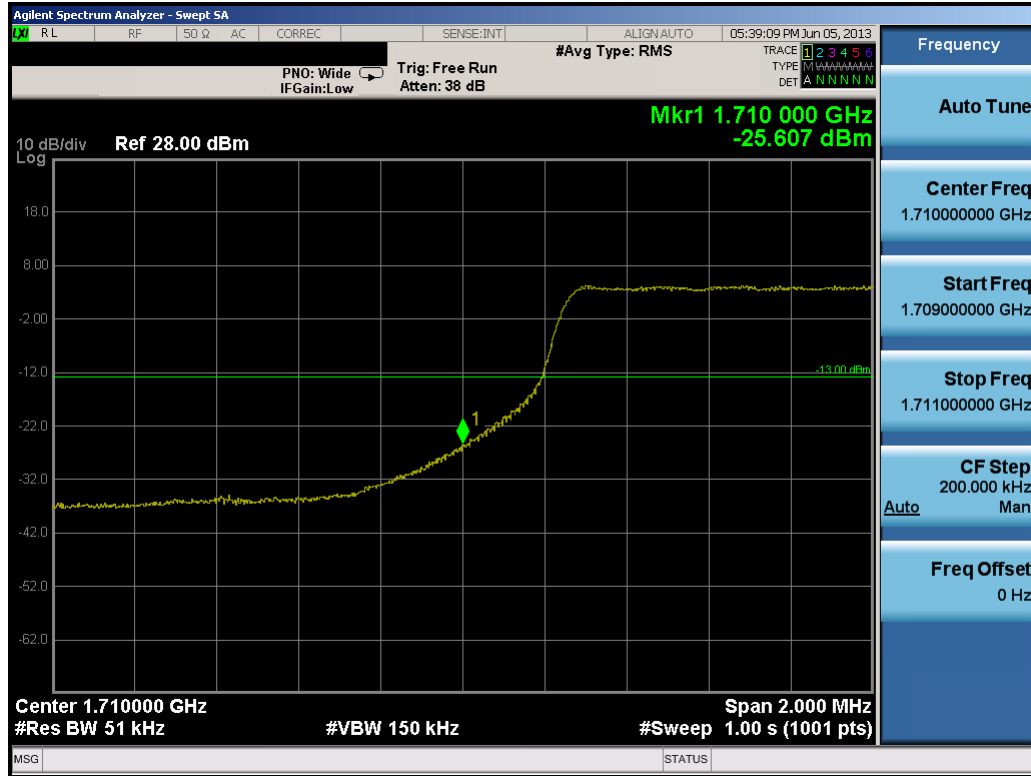


10.0 BAND 4 PLOTS OF EMISSIONS

Note: All bandwidths, RB configurations, and modulations were investigated. The worst case test results are reported below.

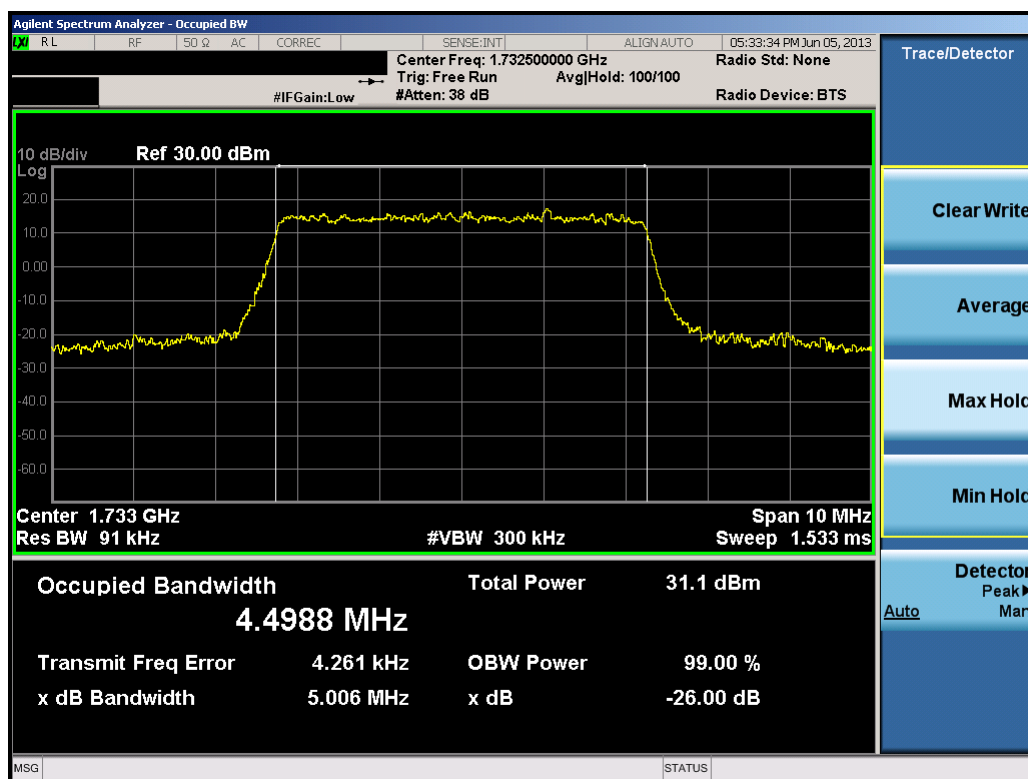


Plot 10-1. Lower Band Edge Plot (5.0MHz QPSK – RB Size 25)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 88 of 133

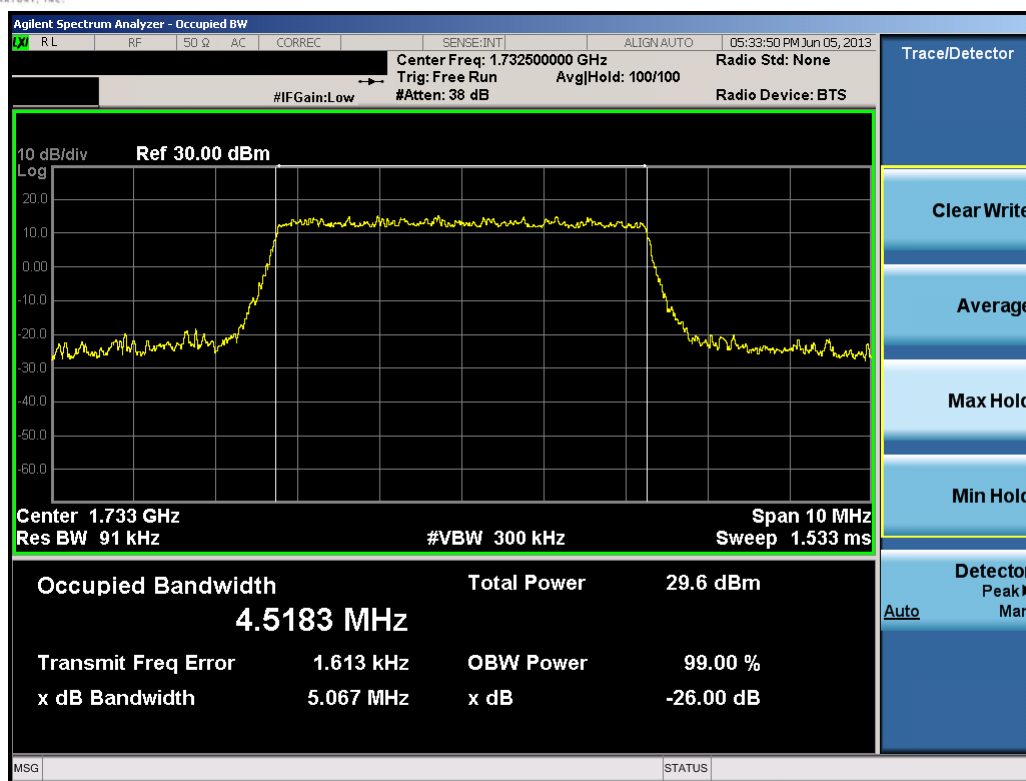


Plot 10-2. Lower Extended Band Edge Plot (5.0MHz QPSK – RB Size 25)

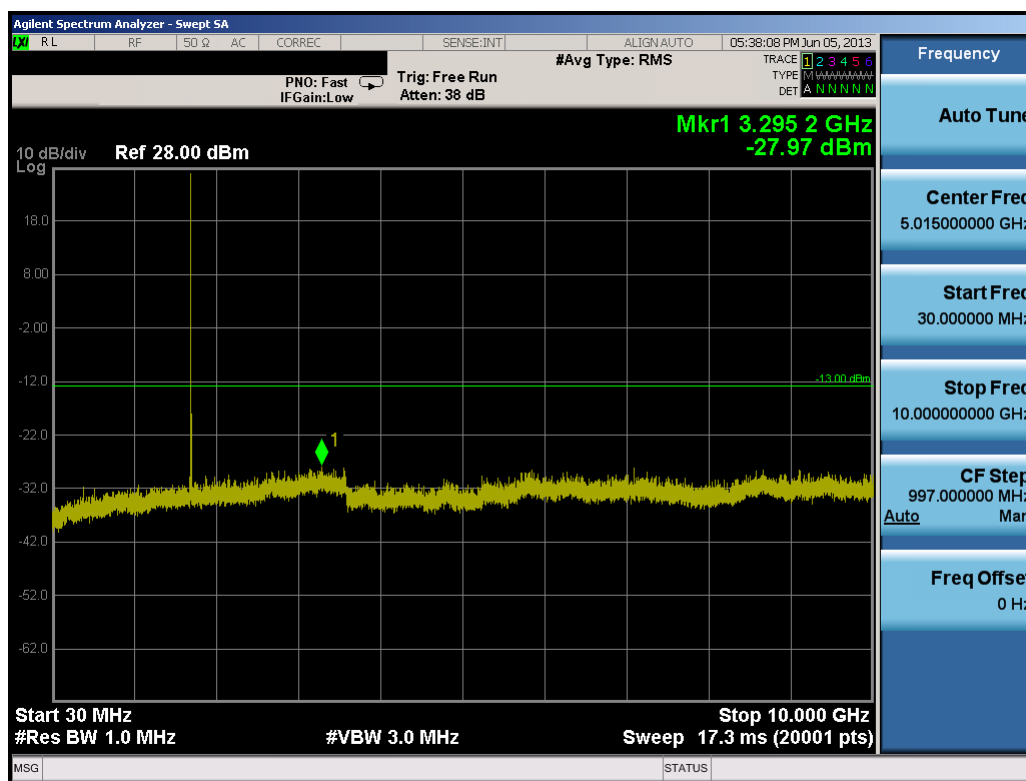


Plot 10-3. Occupied Bandwidth Plot (5.0MHz QPSK – RB Size 25)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 89 of 133

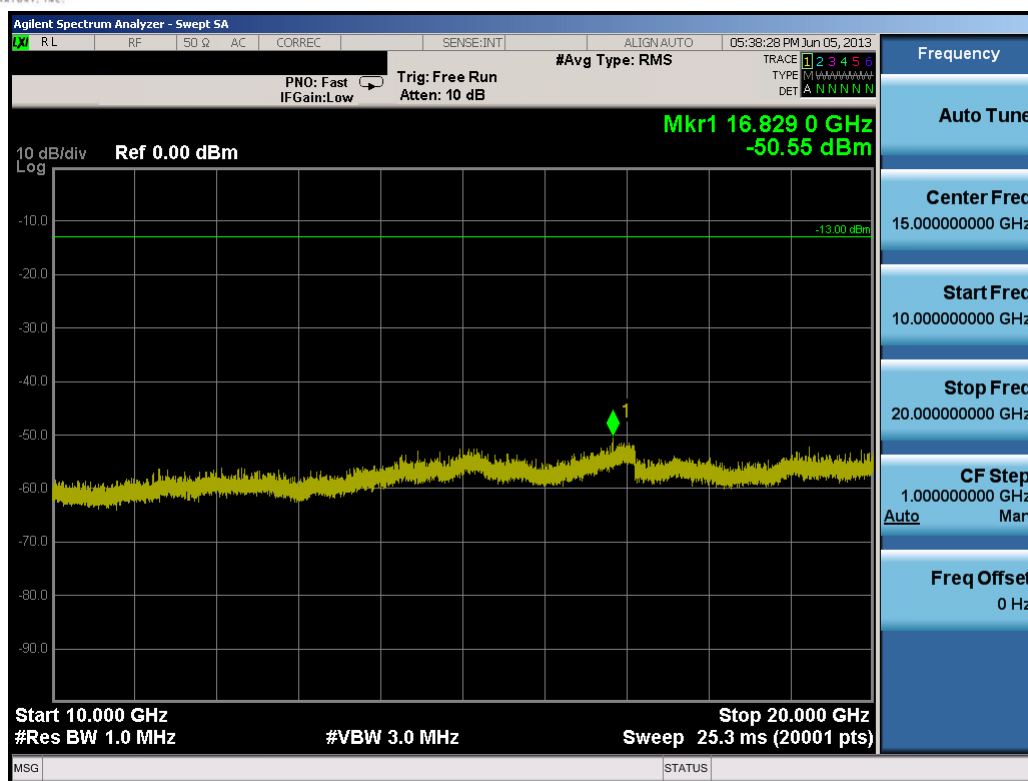


Plot 10-4. Occupied Bandwidth Plot (5.0MHz 16-QAM – RB Size 25)

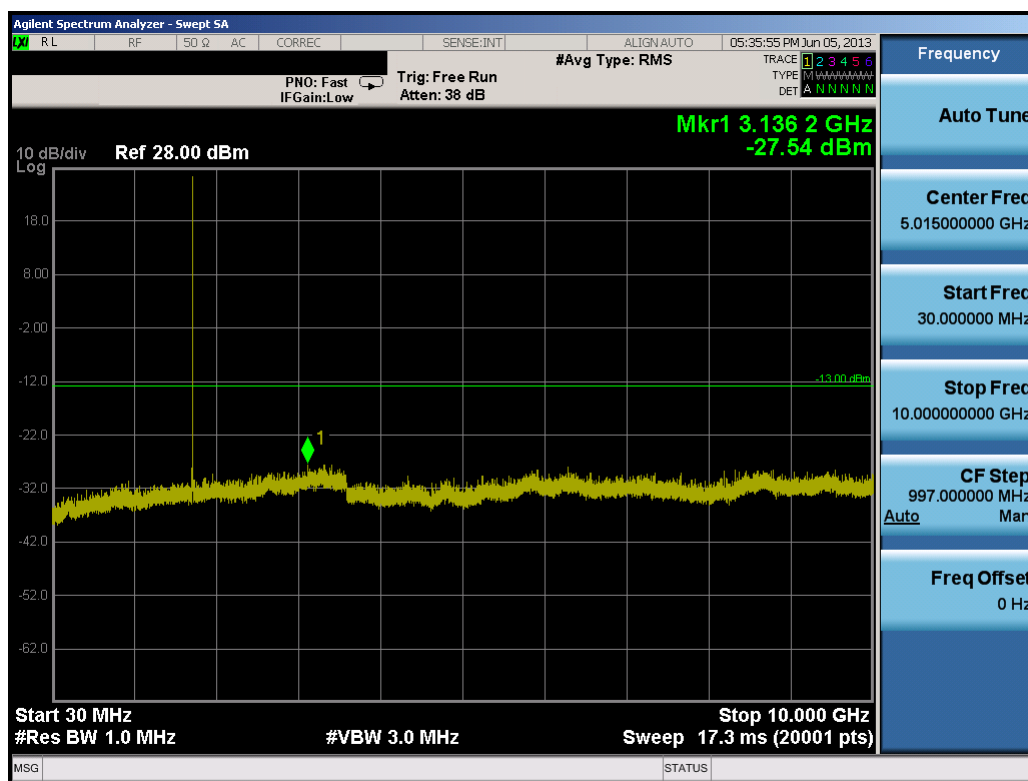


Plot 10-5. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 90 of 133

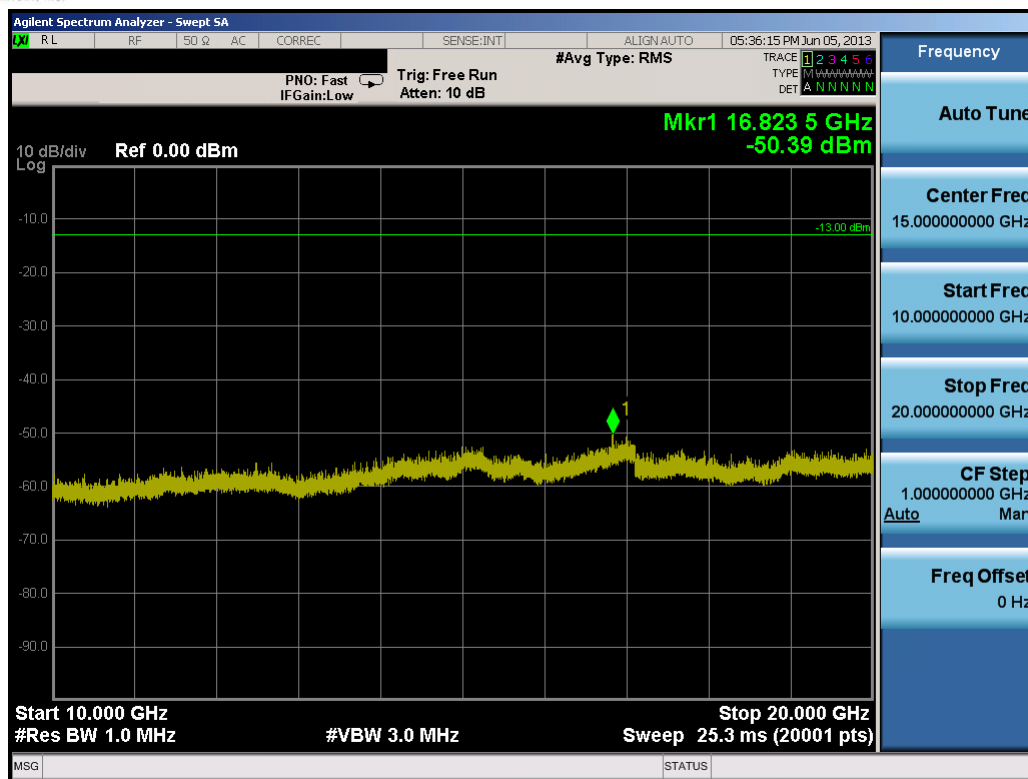


Plot 10-6. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

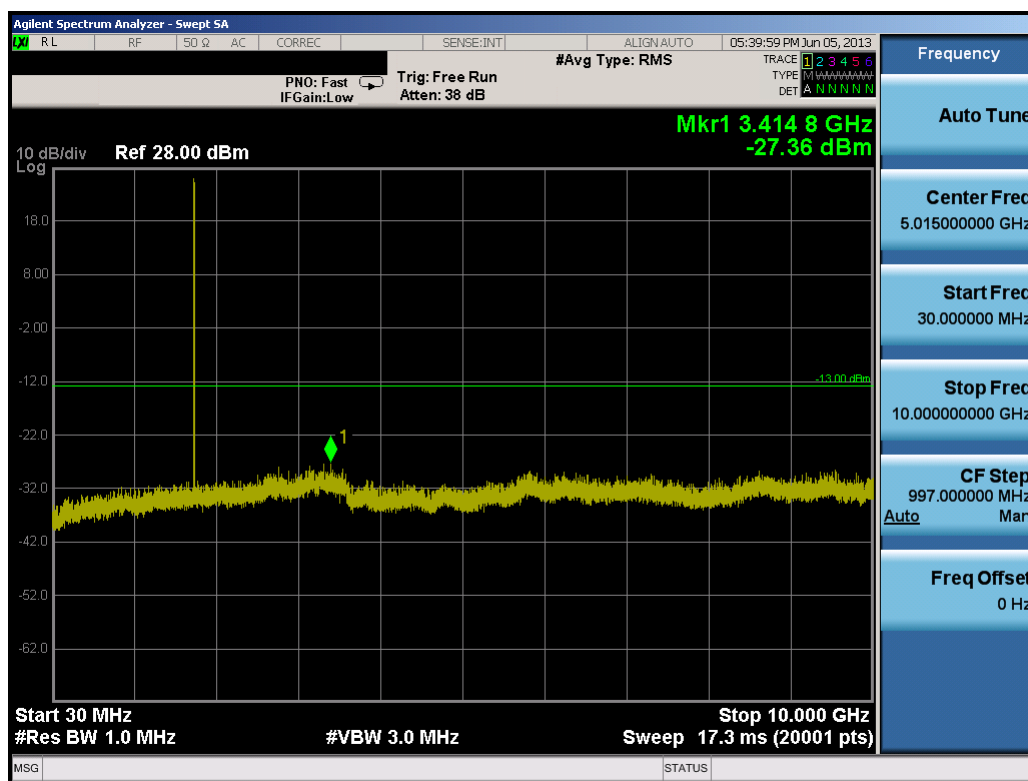


Plot 10-7. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 91 of 133

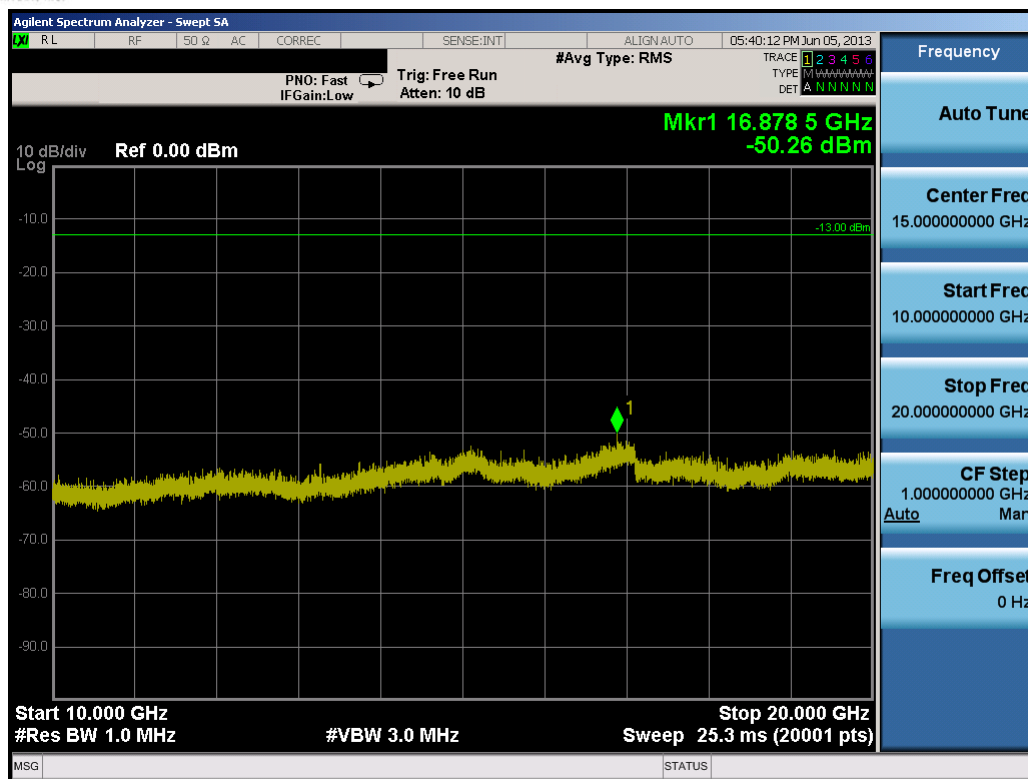


Plot 10-8. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 10-9. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 92 of 133

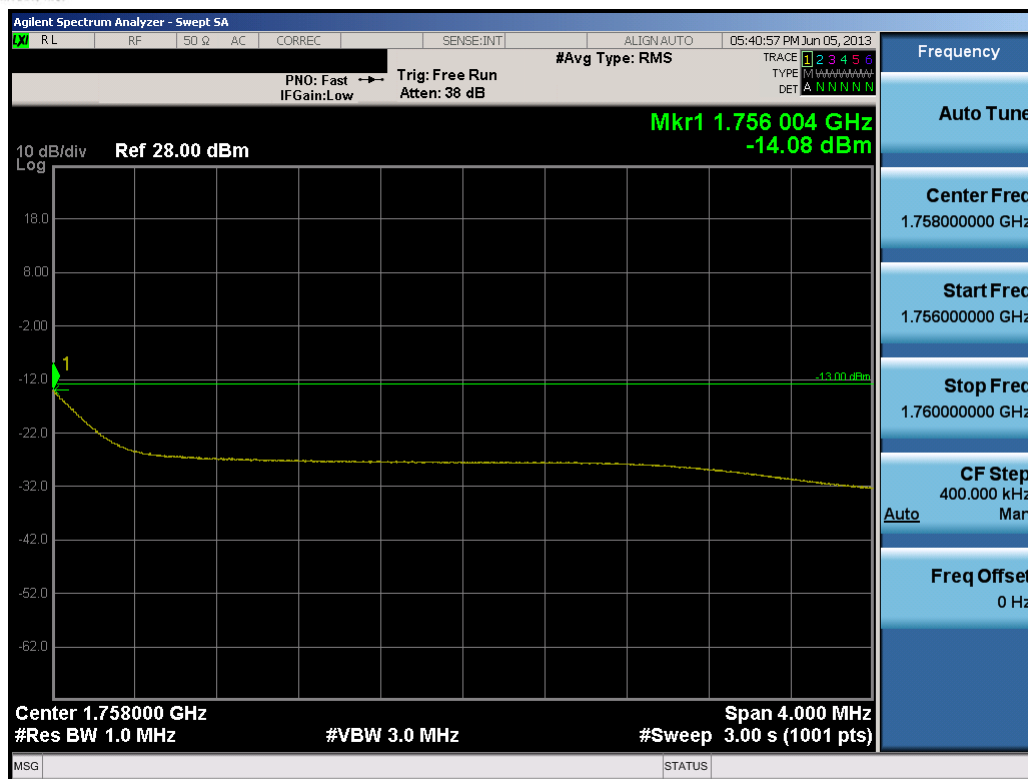


Plot 10-10. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

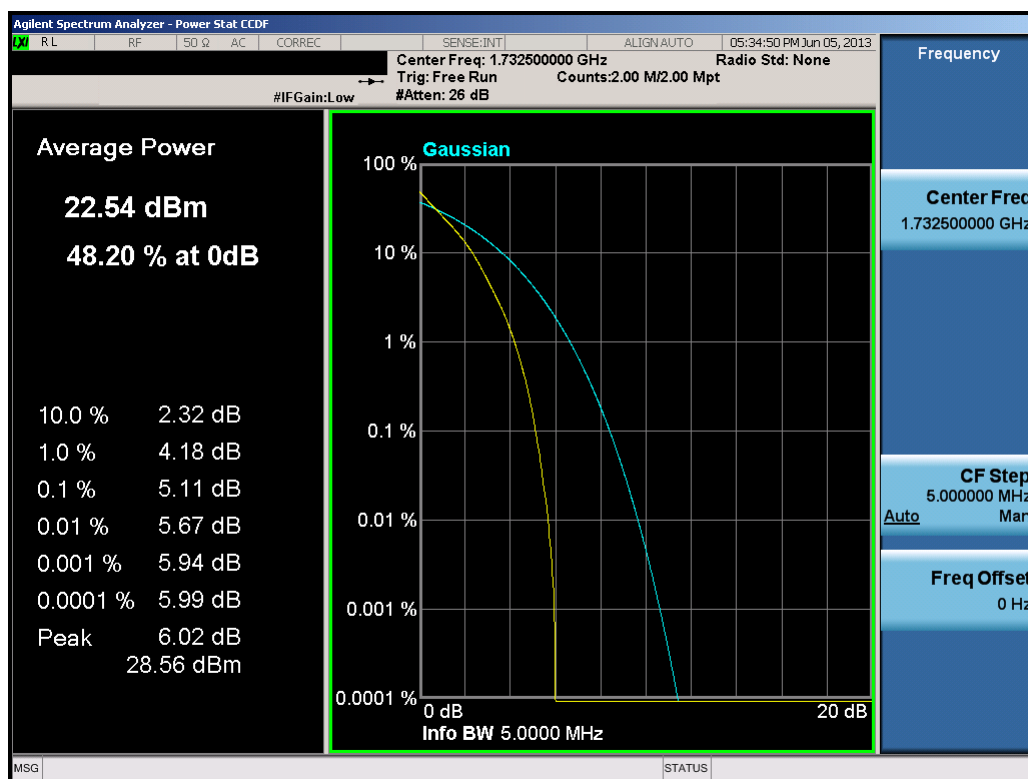


Plot 10-11. Upper Band Edge Plot (5.0MHz QPSK – RB Size 25)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 93 of 133

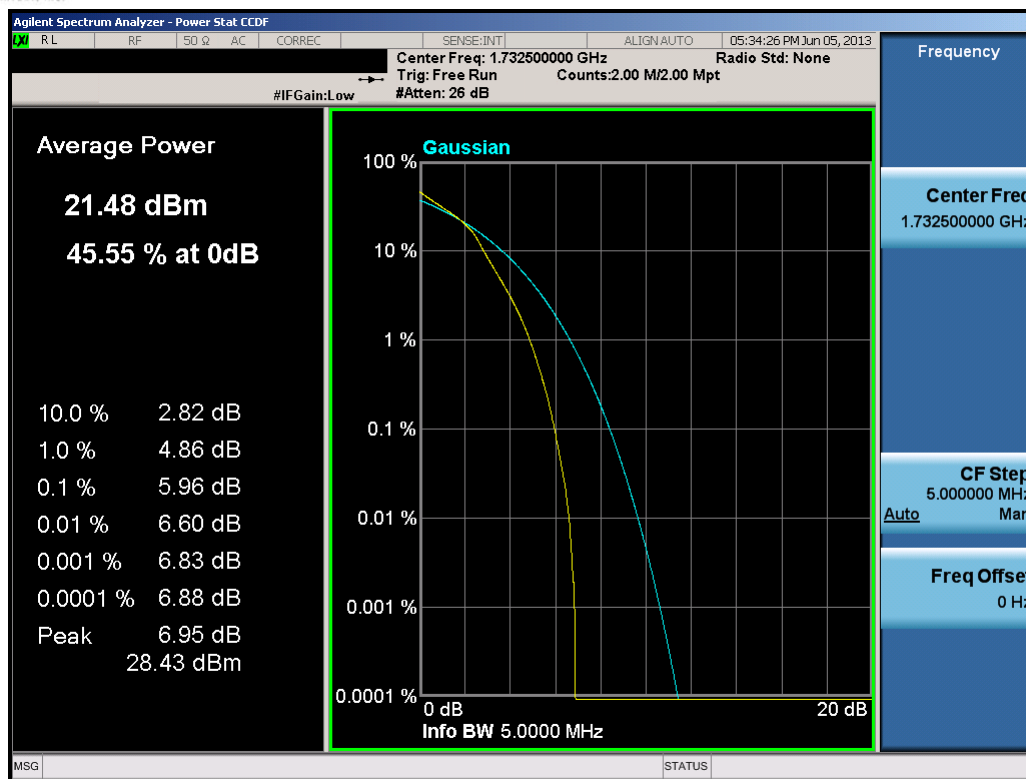


Plot 10-12. Upper Extended Band Edge Plot (5.0MHz QPSK – RB Size 25)



Plot 10-13. PAR Plot (5.0MHz QPSK – RB Size 25)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 94 of 133

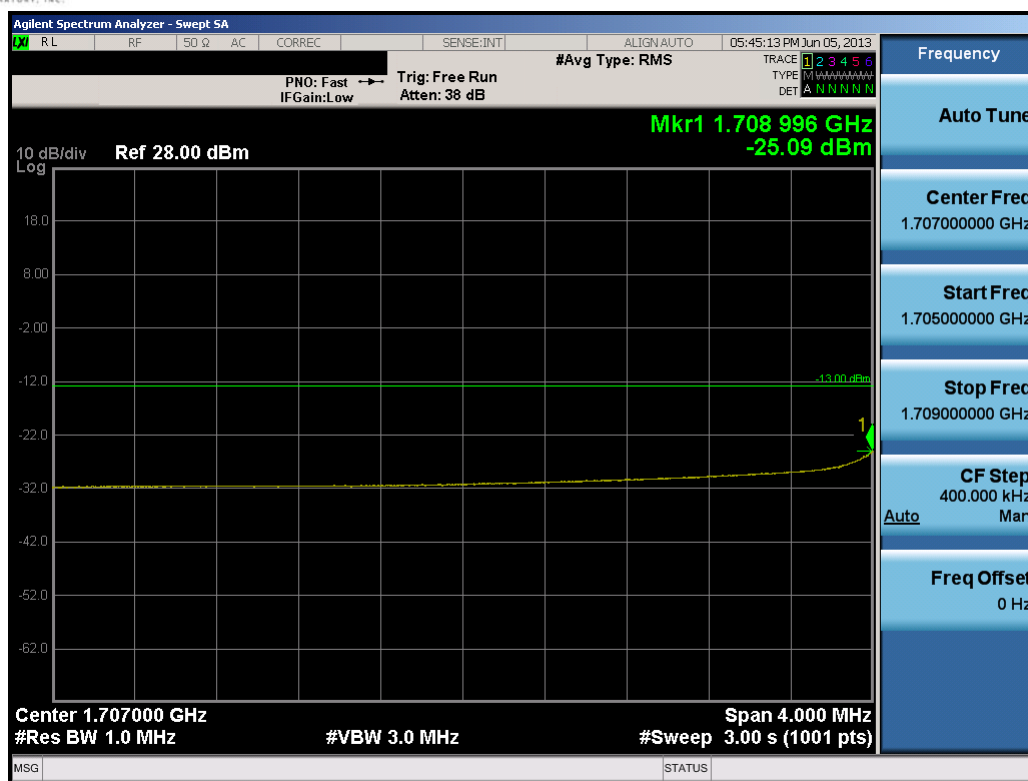


Plot 10-14. PAR Plot (5.0MHz 16-QAM – RB Size 25)

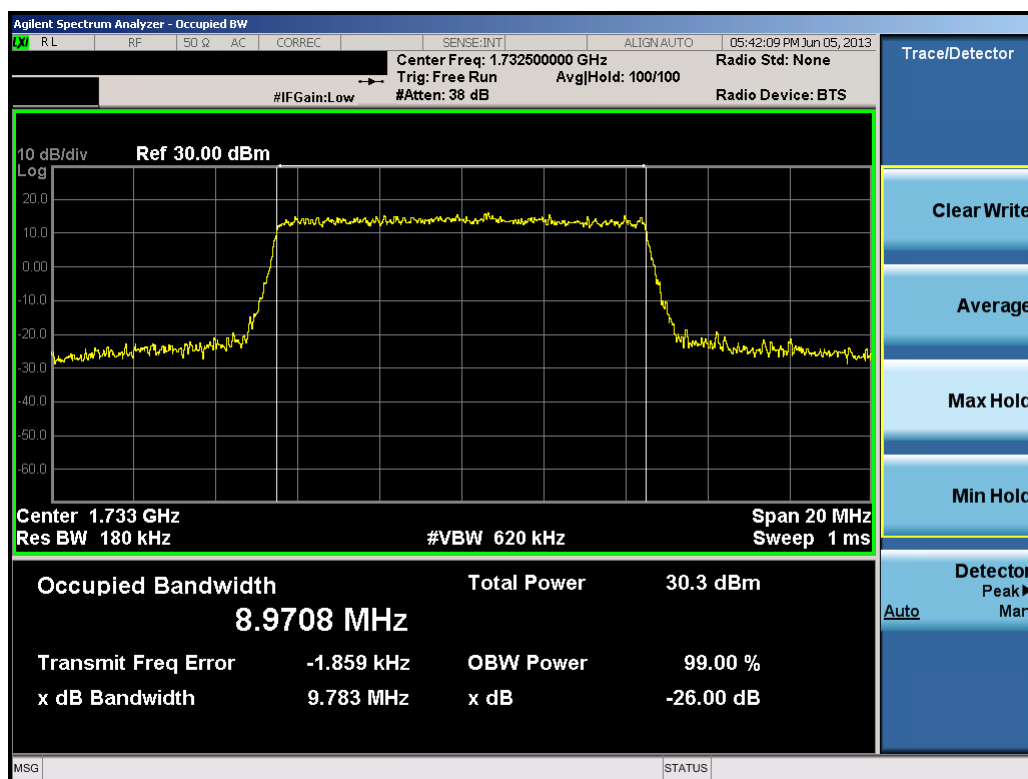


Plot 10-15. Lower Band Edge Plot (10.0MHz QPSK – RB Size 50)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 95 of 133

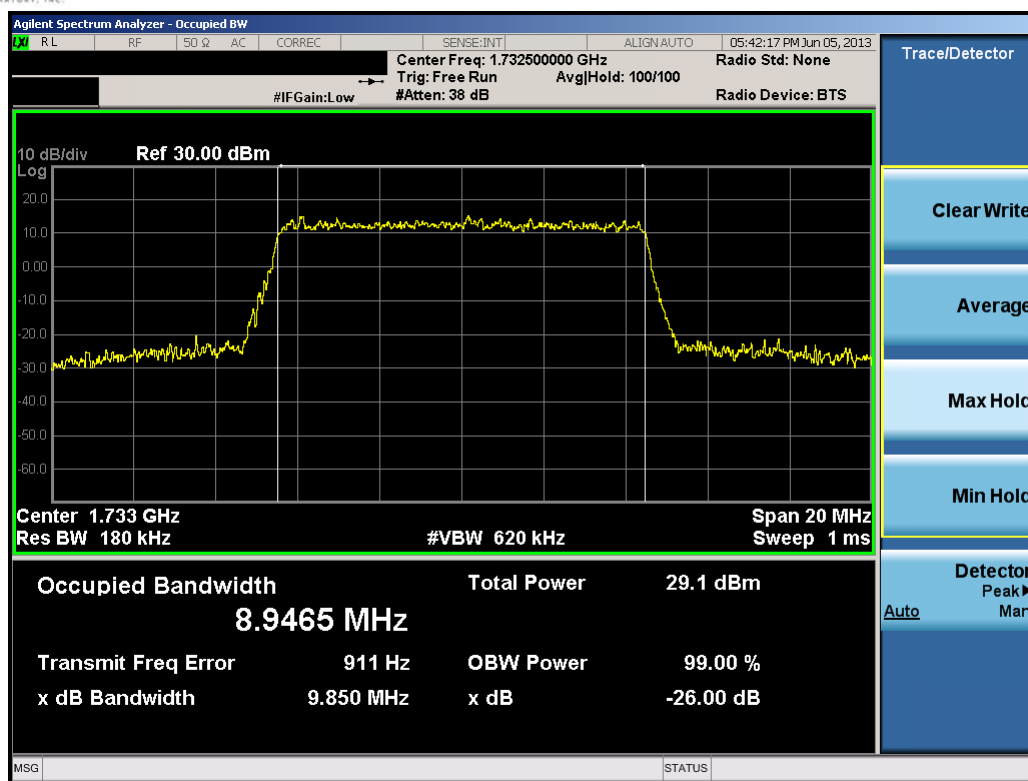


Plot 10-16. Lower Extended Band Edge Plot (10.0MHz QPSK – RB Size 50)

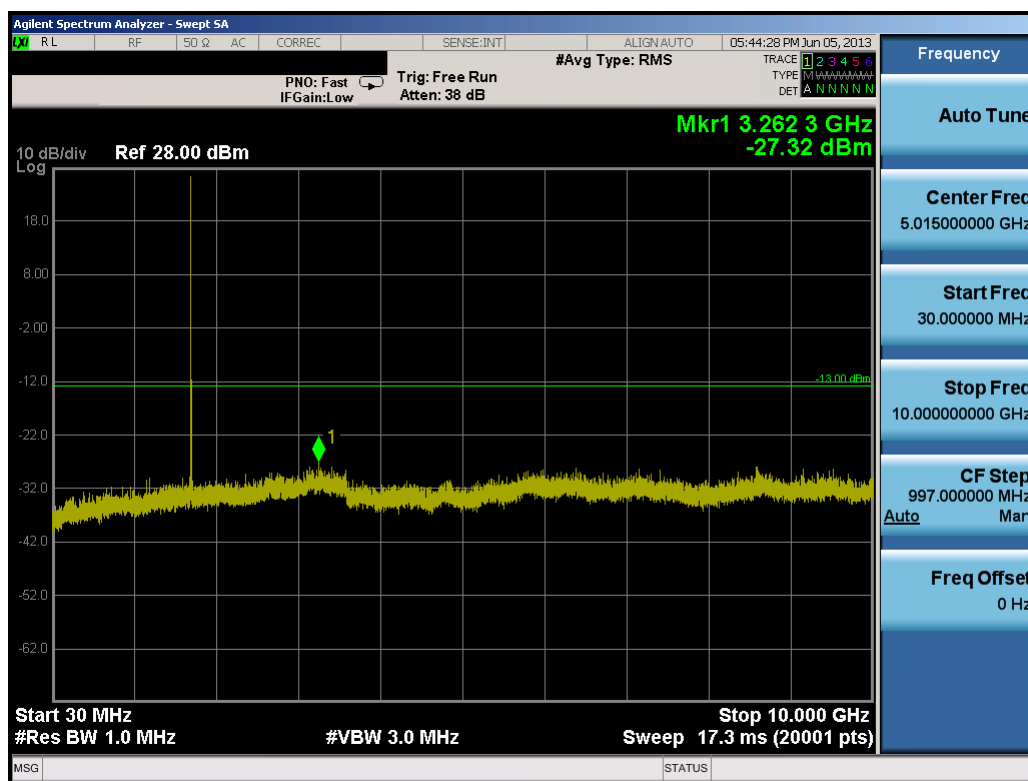


Plot 10-17. Occupied Bandwidth Plot (10.0MHz QPSK – RB Size 50)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 96 of 133

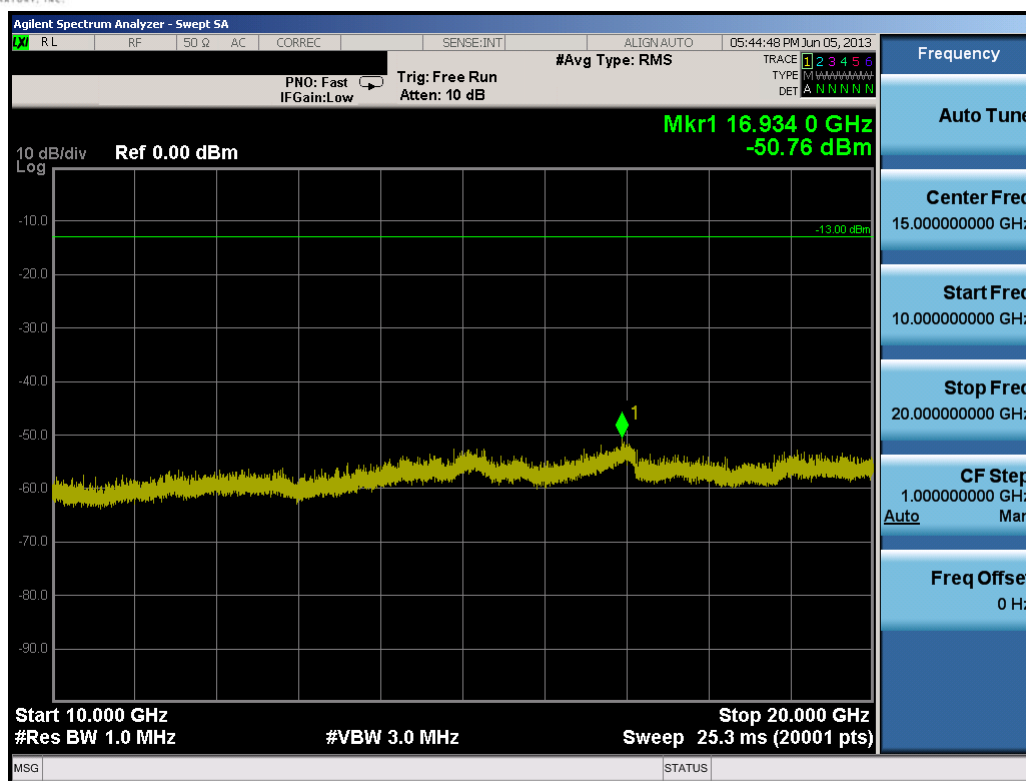


Plot 10-18. Occupied Bandwidth Plot (10.0MHz 16-QAM – RB Size 50)

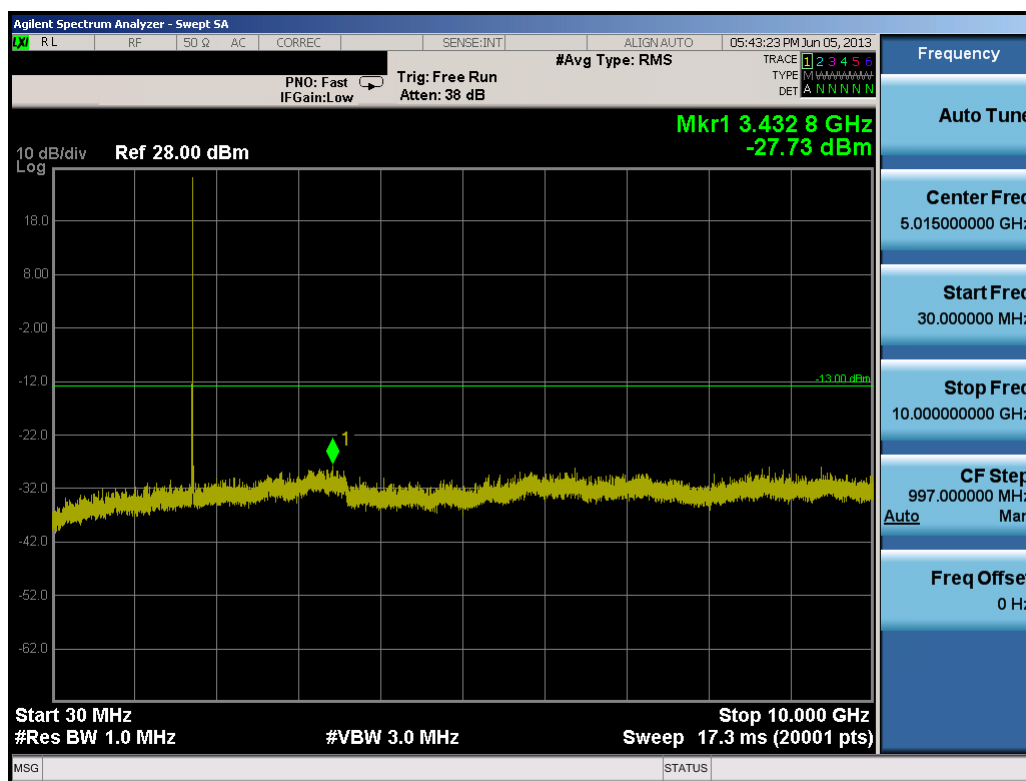


Plot 10-19. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0– Low Channel)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 97 of 133

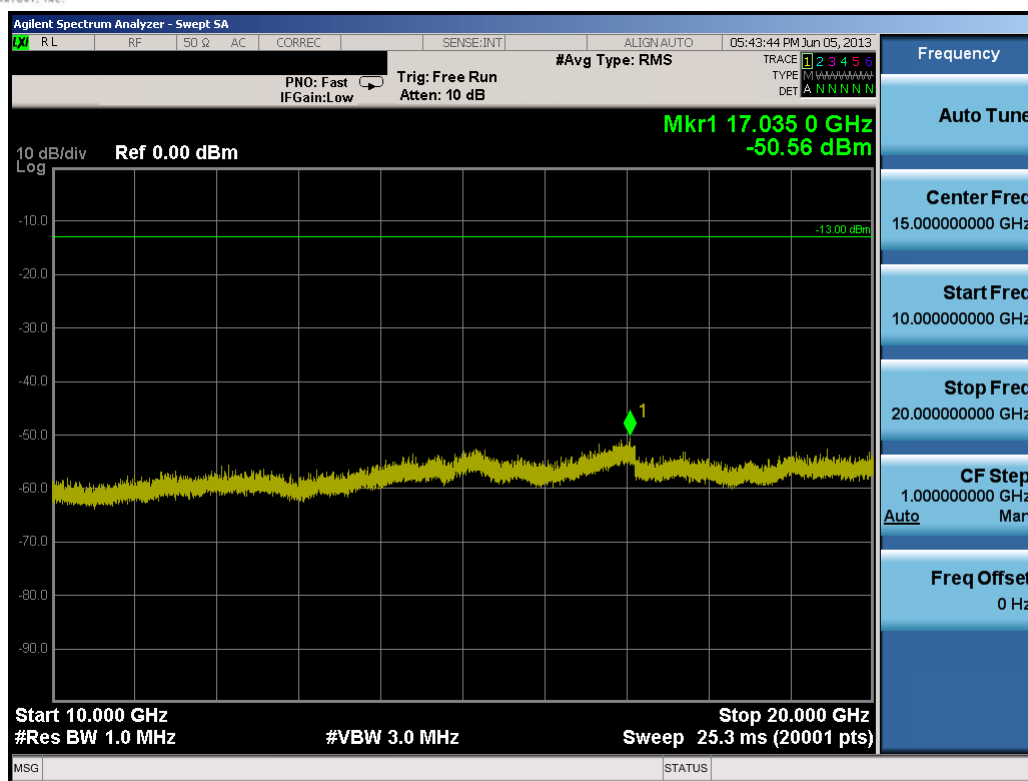


Plot 10-20. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

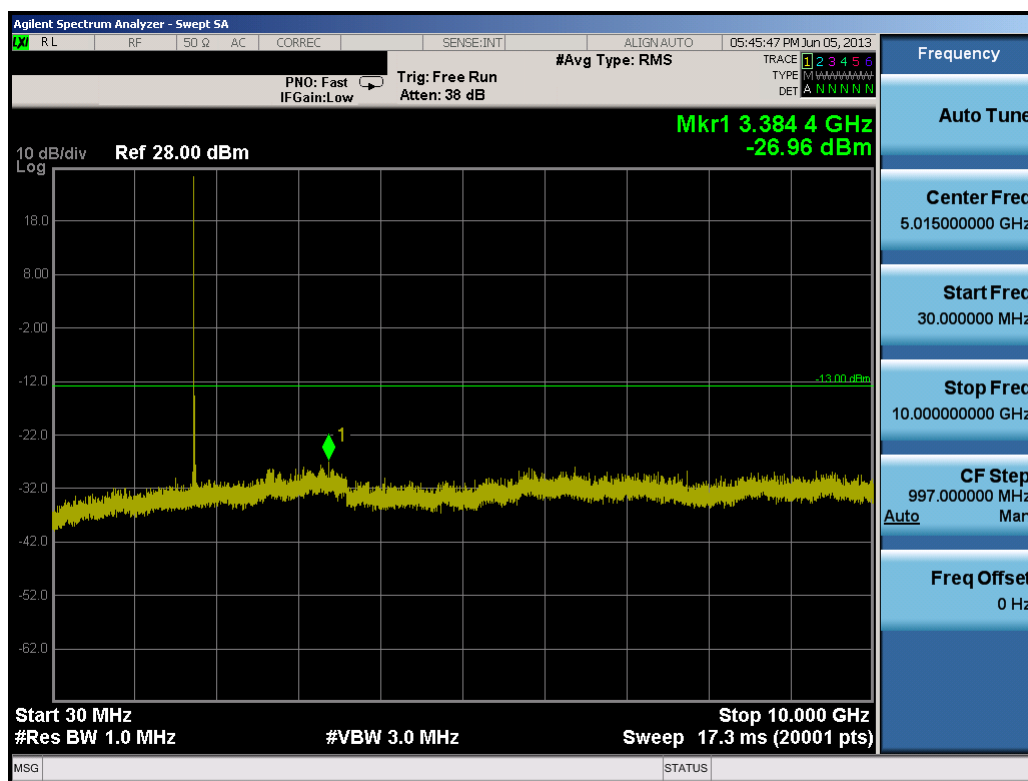


Plot 10-21. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSCHR960	 FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION) 		Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset	Page 98 of 133

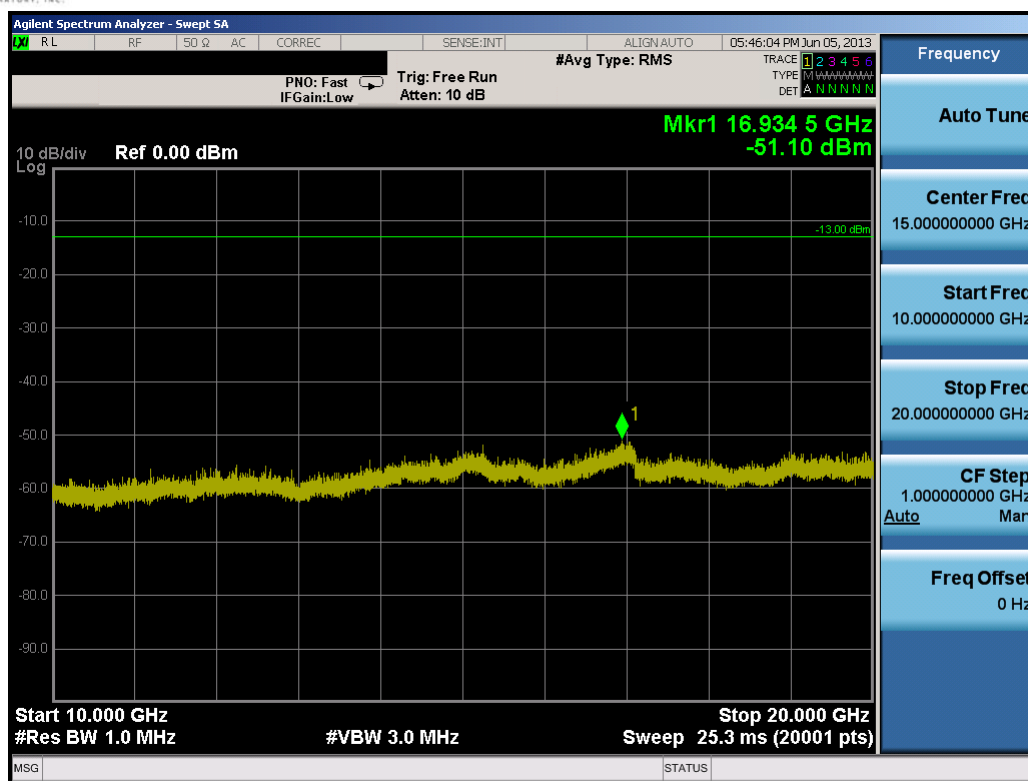


Plot 10-22. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

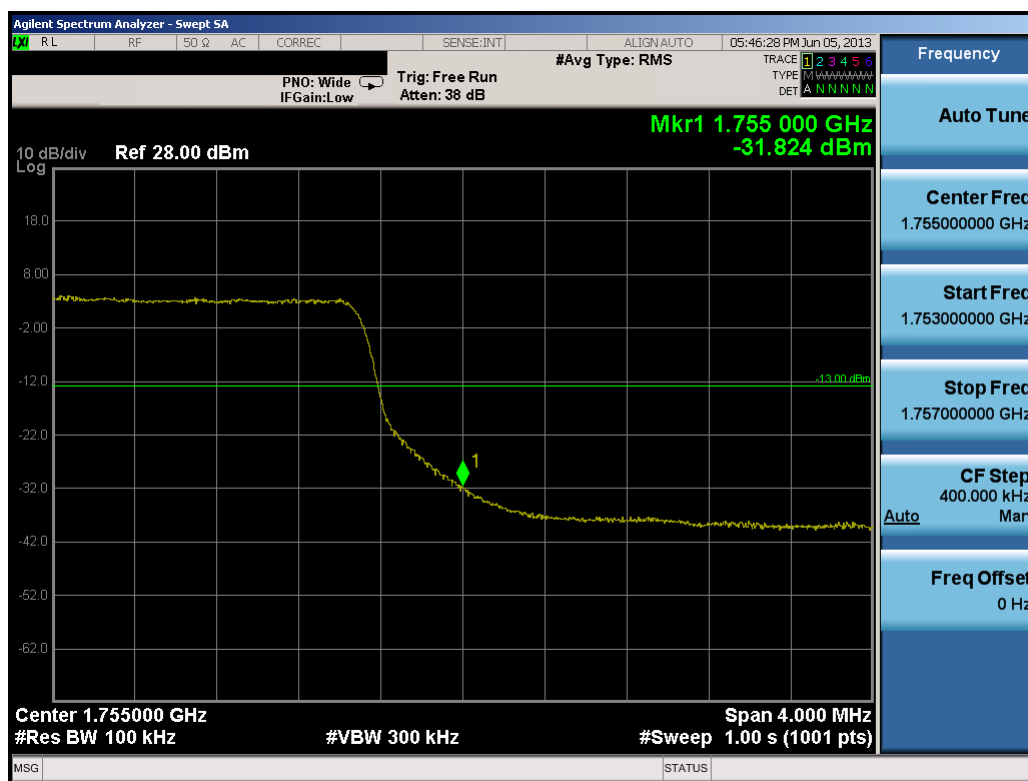


Plot 10-23. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 99 of 133

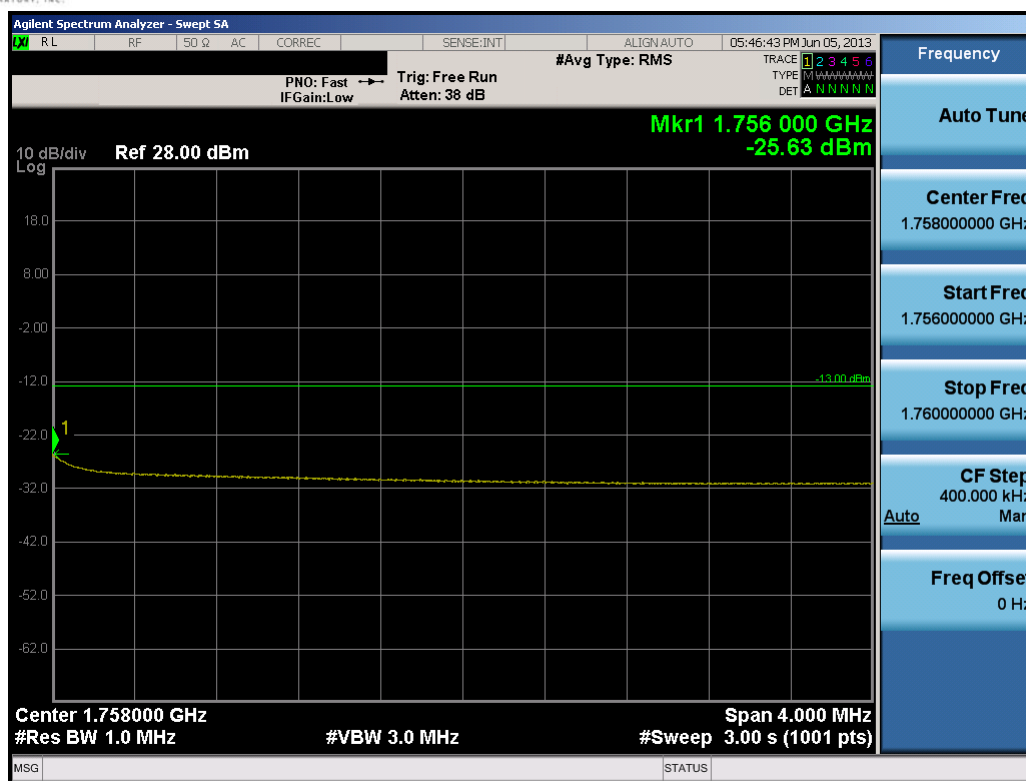


Plot 10-24. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

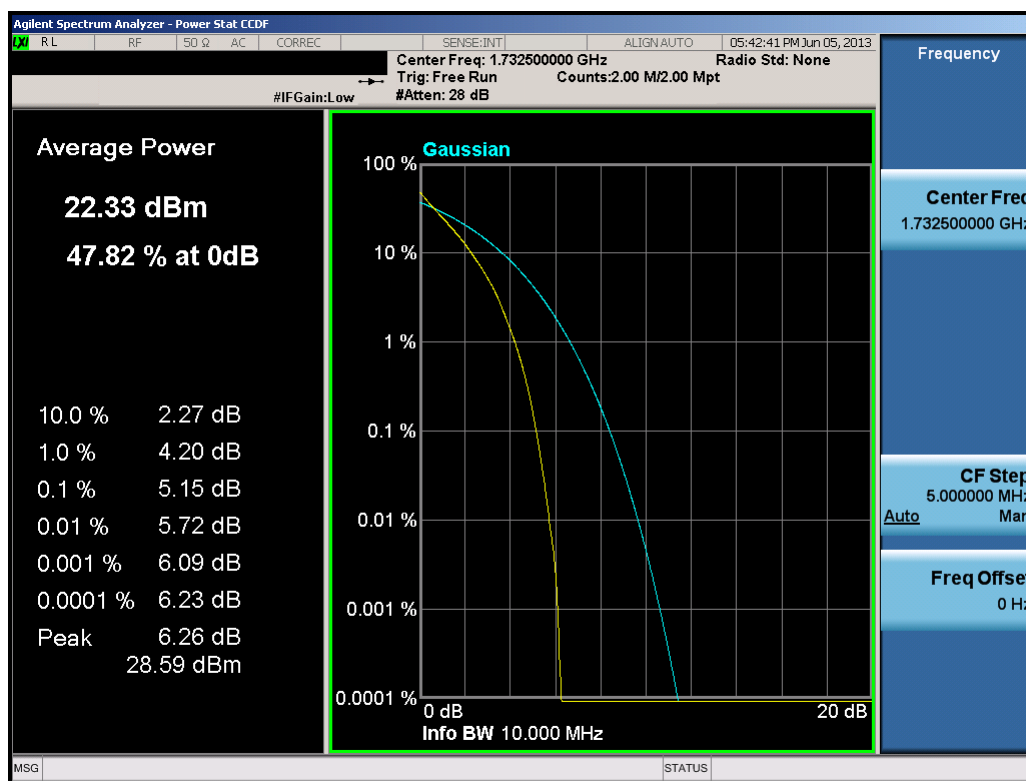


Plot 10-25. Upper Band Edge Plot (10.0MHz QPSK – RB Size 50)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 100 of 133

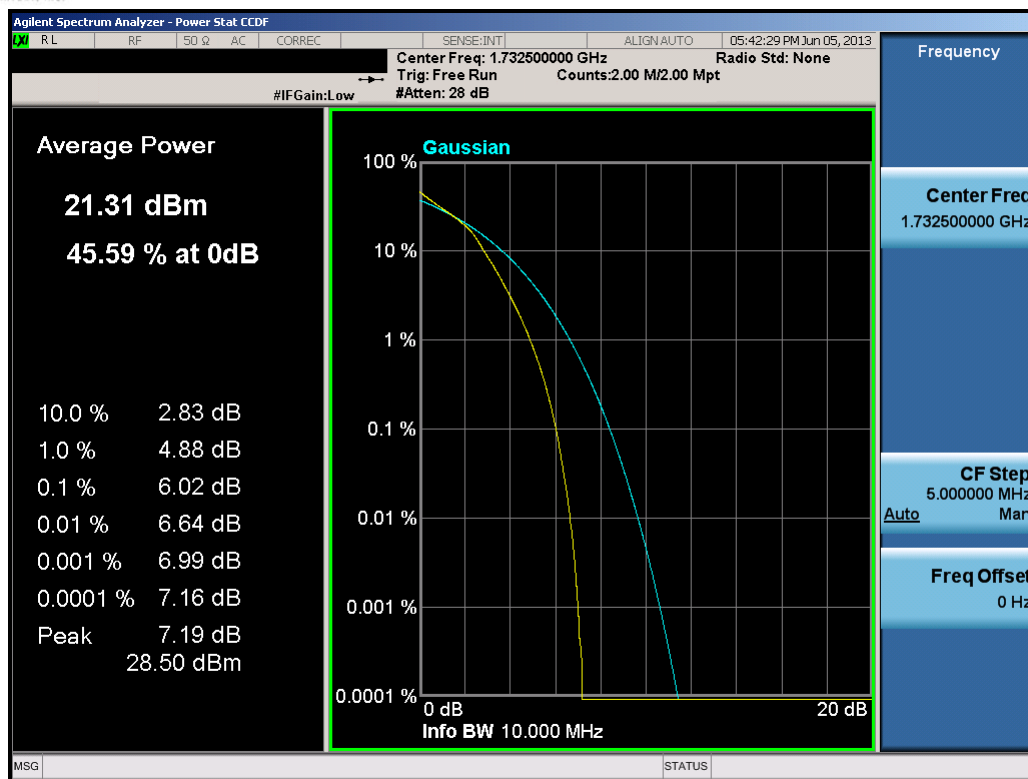


Plot 10-26. Upper Extended Band Edge Plot (10.0MHz QPSK – RB Size 50)



Plot 10-27. PAR Plot (10.0MHz QPSK – RB Size 50)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 101 of 133

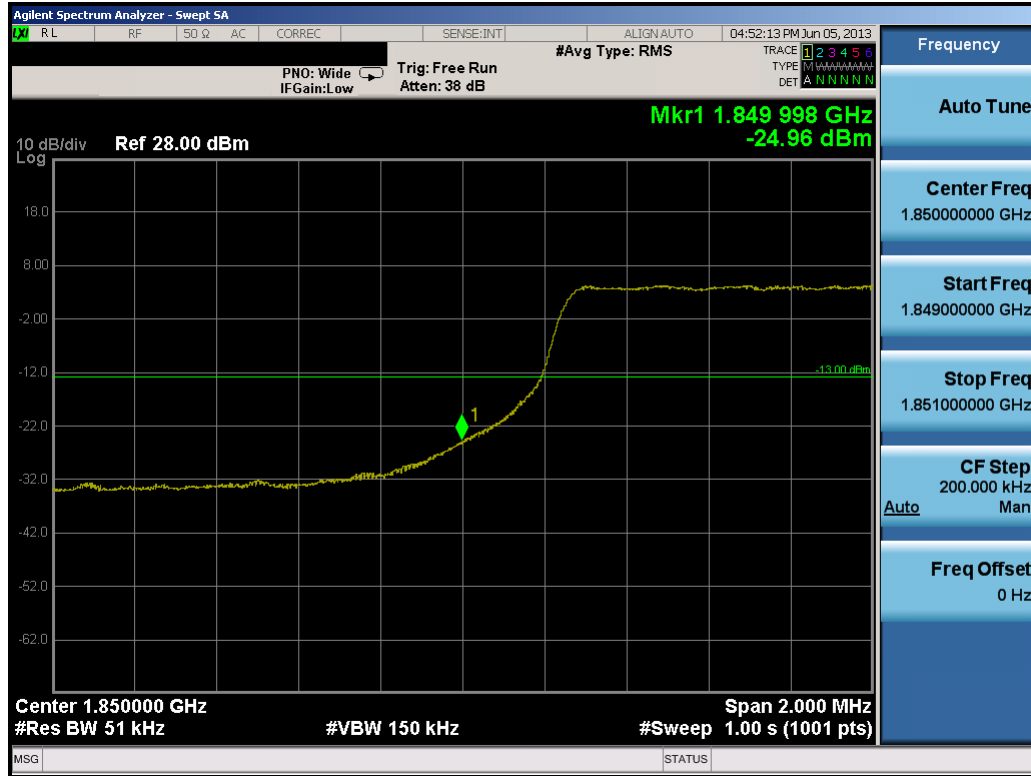


Plot 10-28. PAR Plot (10.0MHz 16-QAM – RB Size 50)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 102 of 133

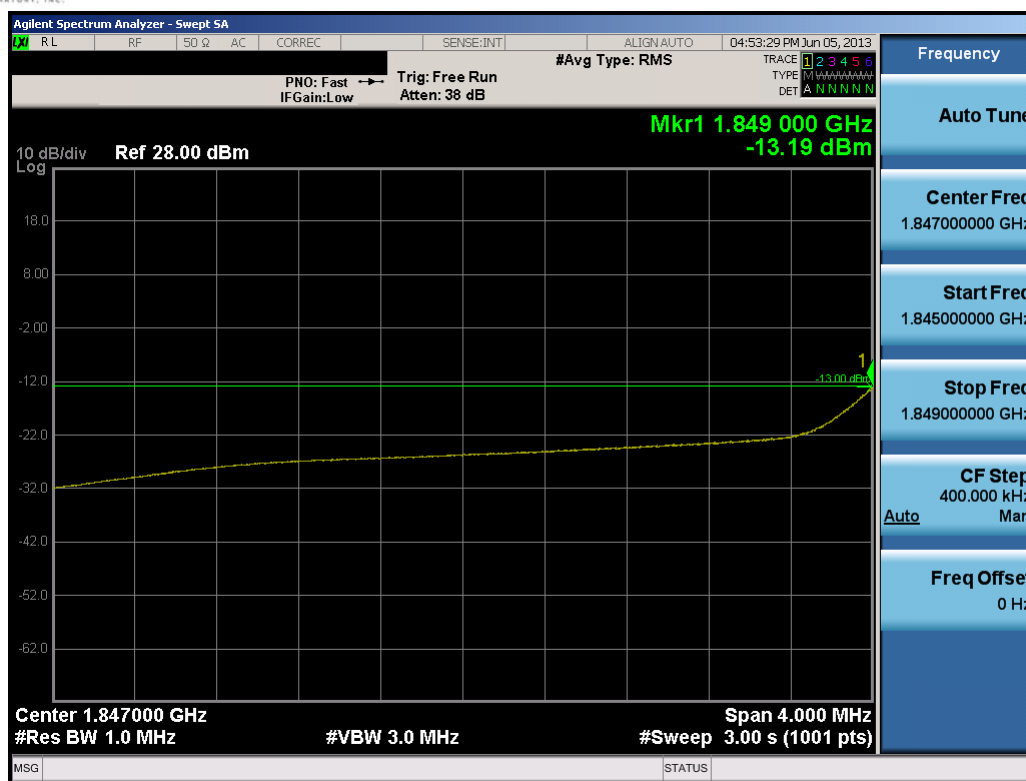
11.0 BAND 2 PLOTS OF EMISSIONS

Note: All bandwidths, RB configurations, and modulations were investigated. The worst case test results are reported below.

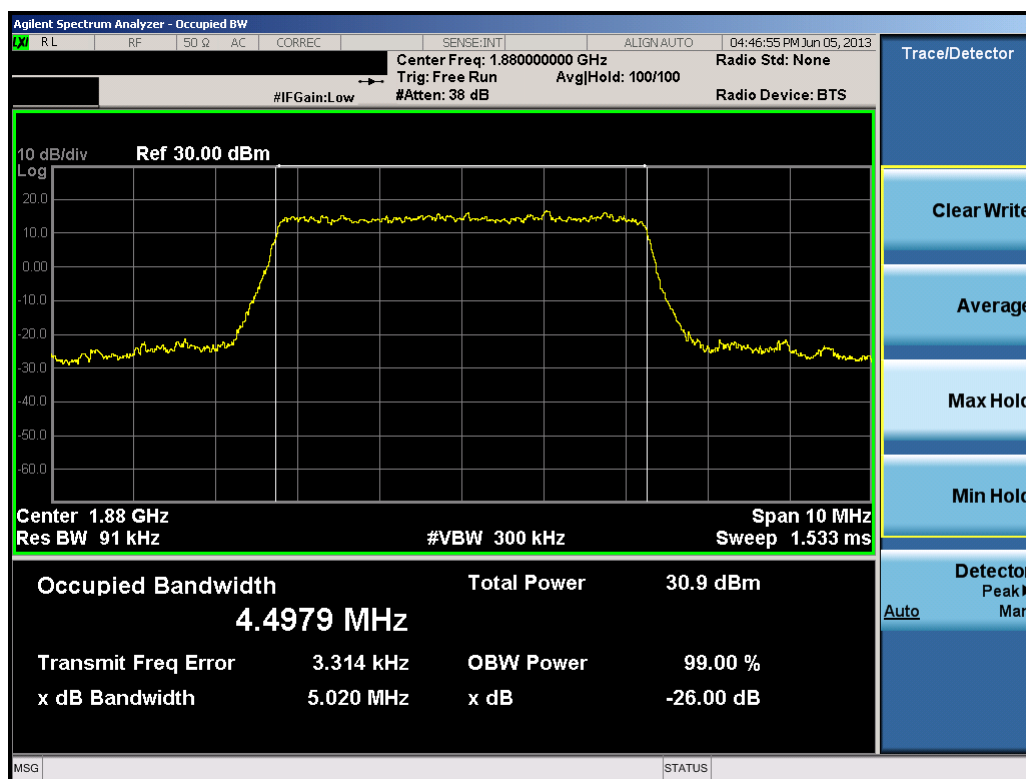


Plot 11-1. Lower Band Edge Plot (5.0MHz QPSK – RB Size 25)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 103 of 133

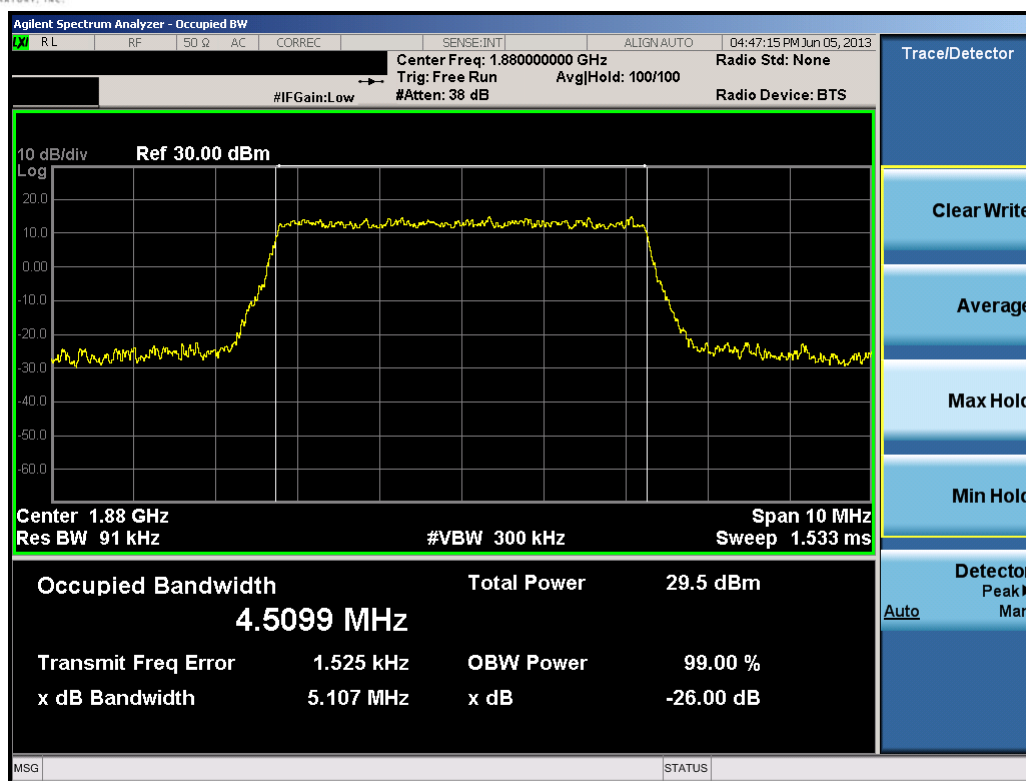


Plot 11-2. Lower Extended Band Edge Plot (5.0MHz QPSK – RB Size 25)

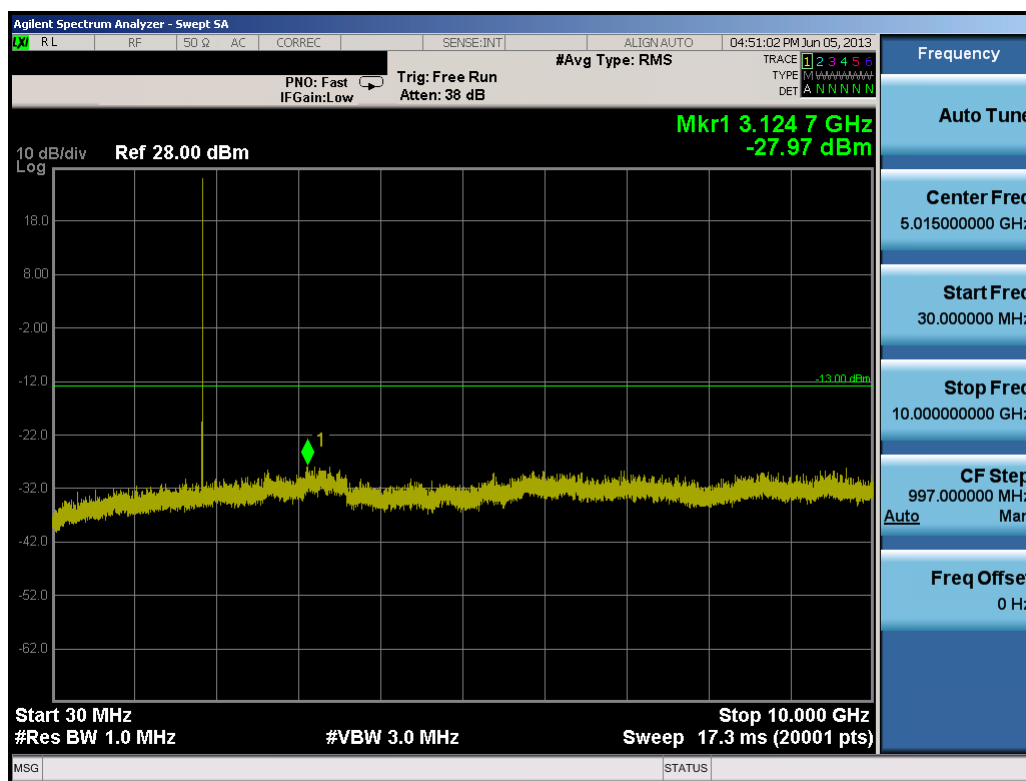


Plot 11-3. Occupied Bandwidth Plot (5.0MHz QPSK – RB Size 25)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 104 of 133

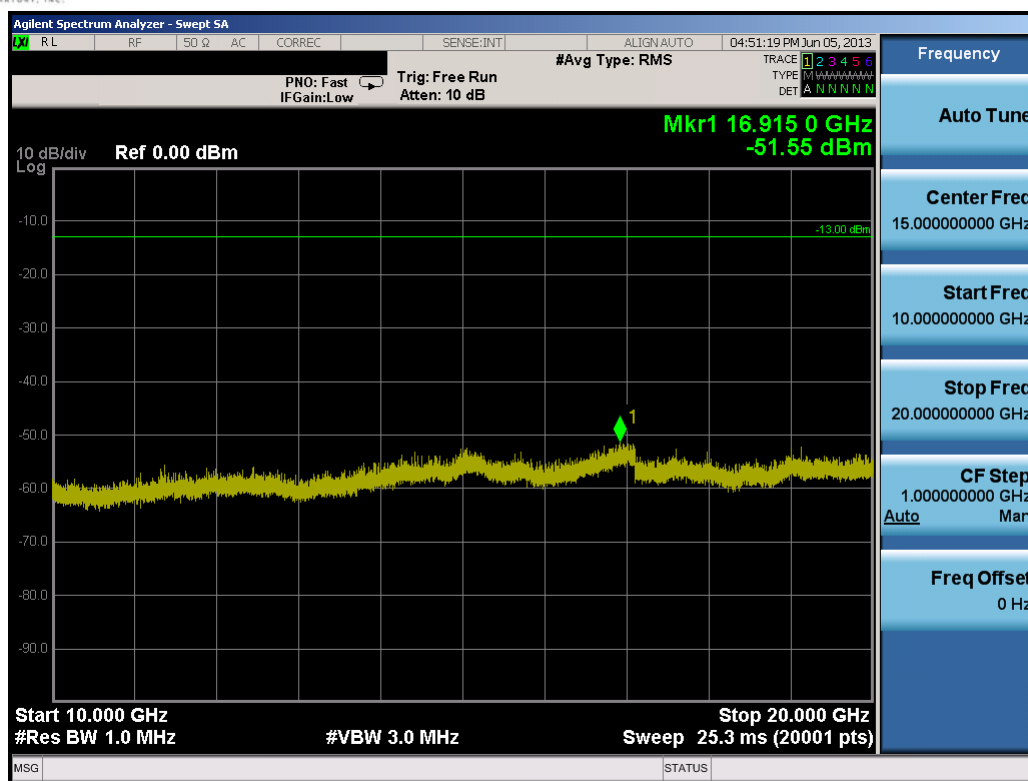


Plot 11-4. Occupied Bandwidth Plot (5.0MHz 16-QAM – RB Size 25)

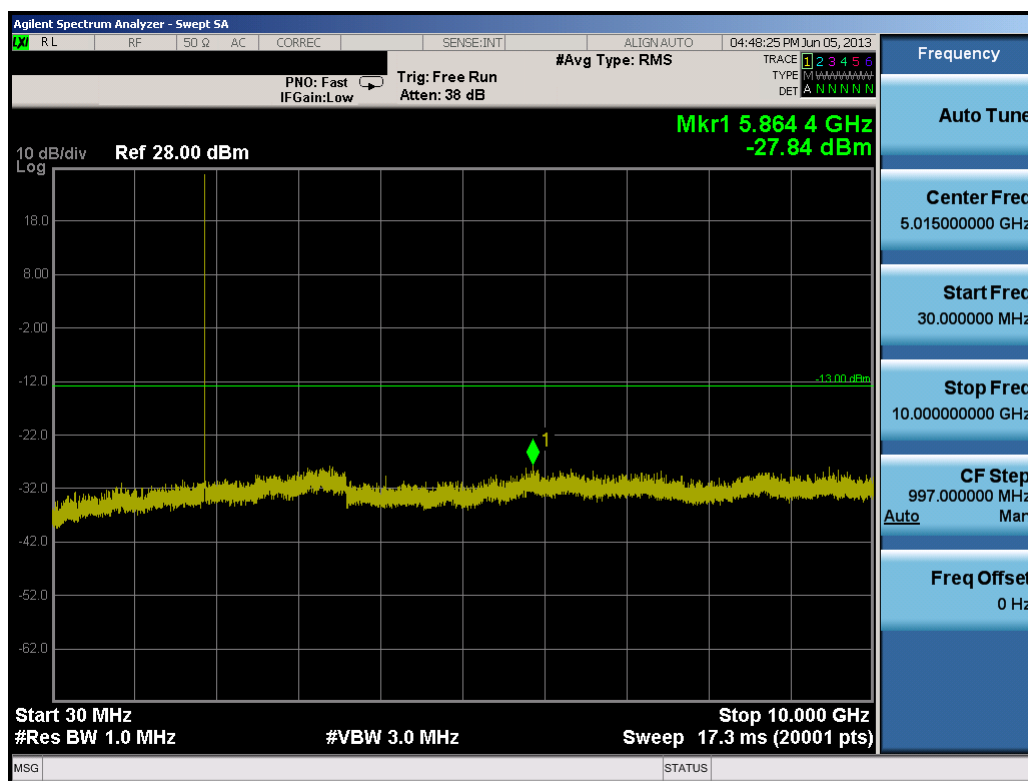


Plot 11-5. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 105 of 133

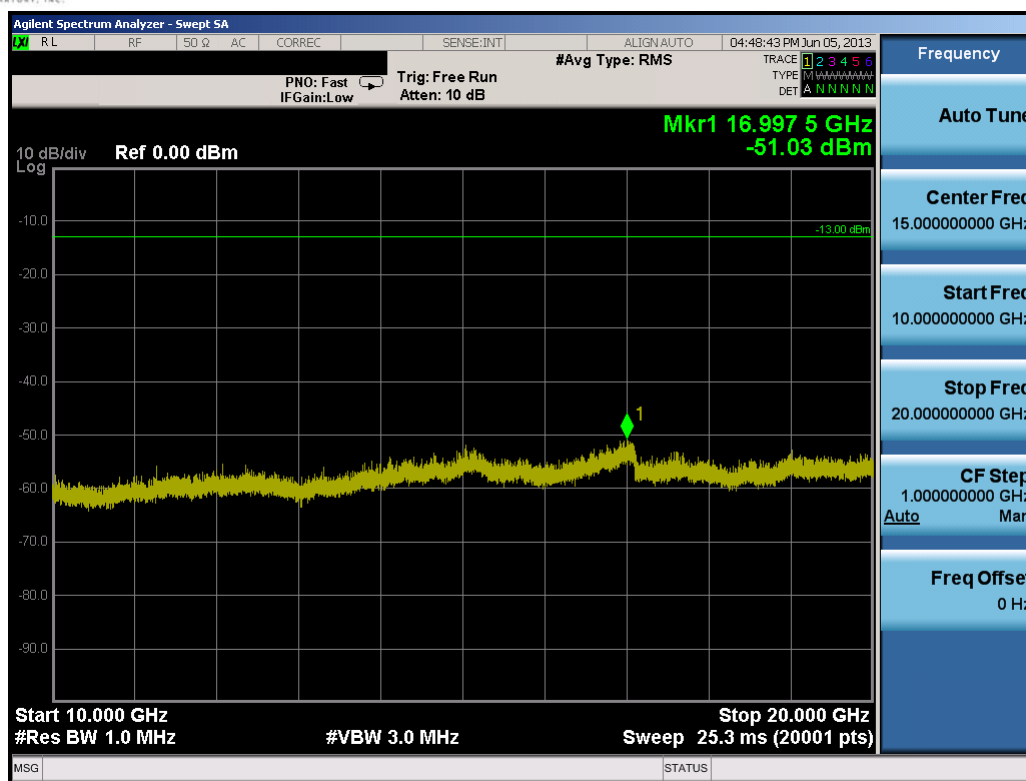


Plot 11-6. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

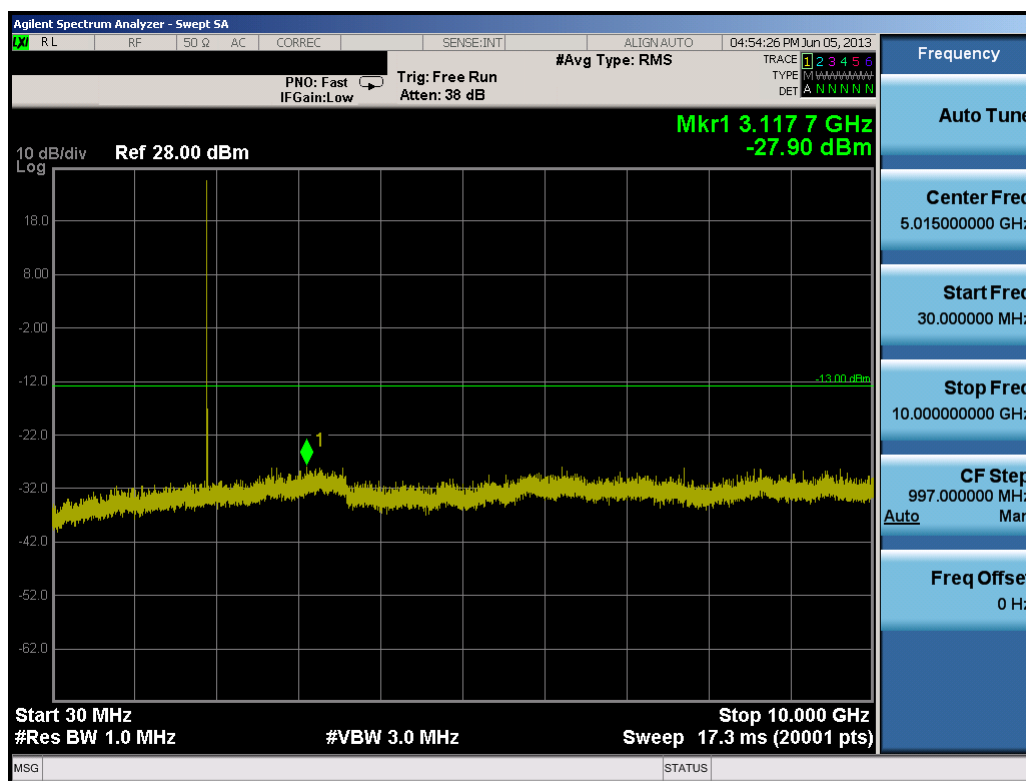


Plot 11-7. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 106 of 133

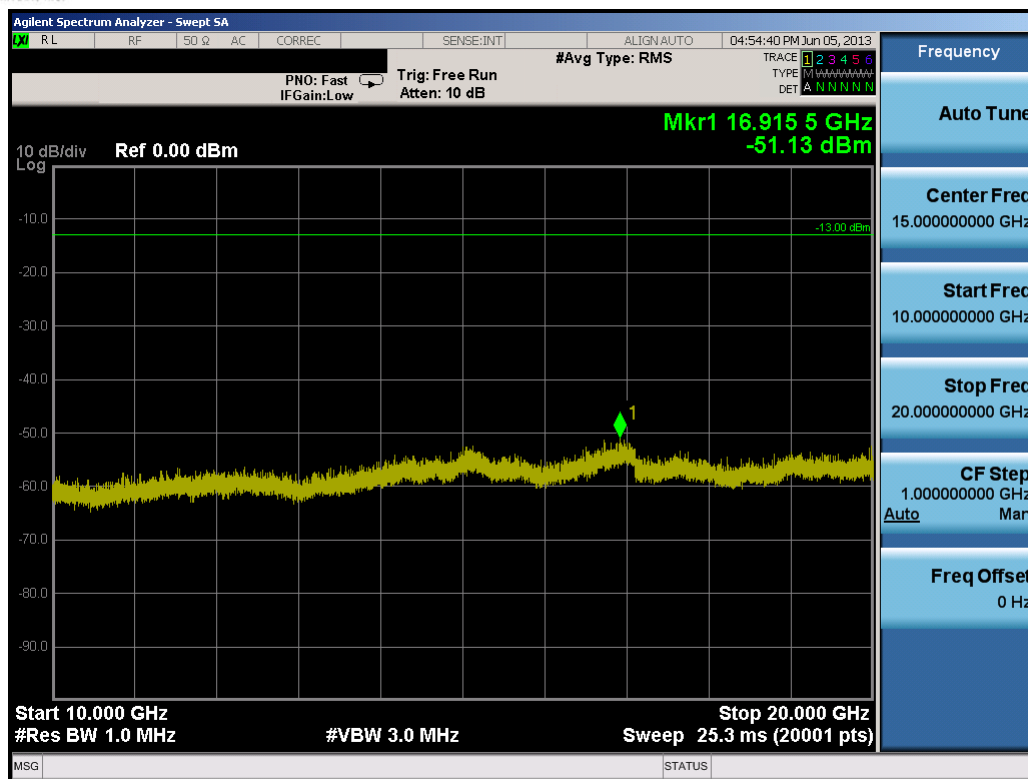


Plot 11-8. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 11-9. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 107 of 133

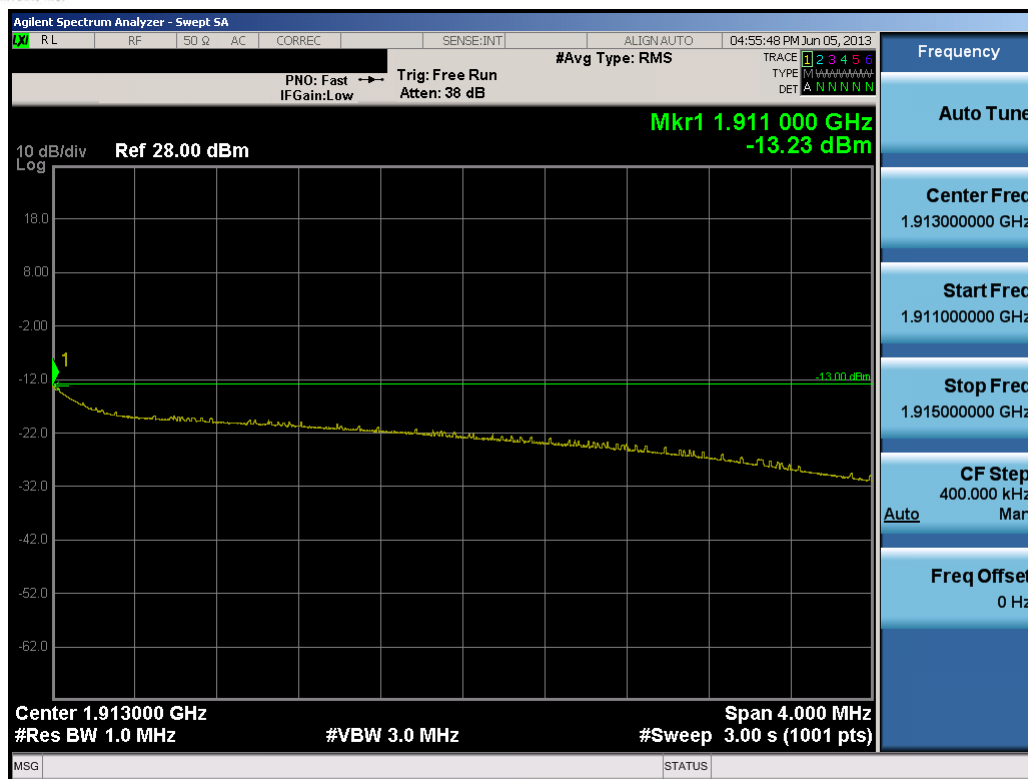


Plot 11-10. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

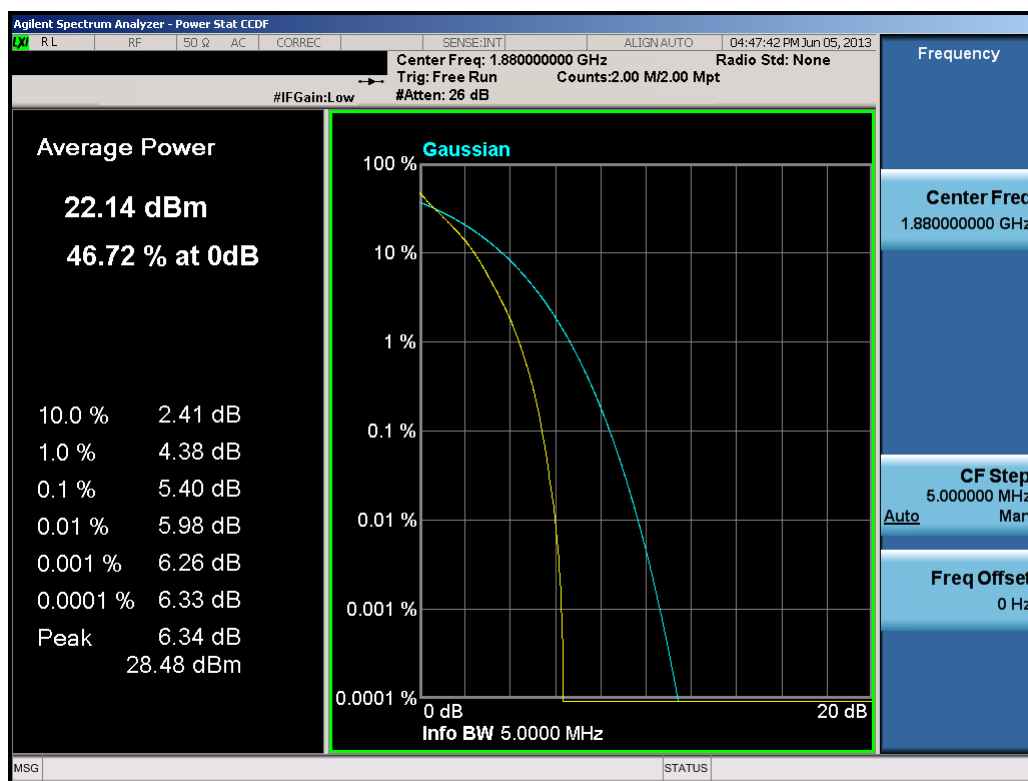


Plot 11-11. Upper Band Edge Plot (5.0MHz QPSK – RB Size 25)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 108 of 133

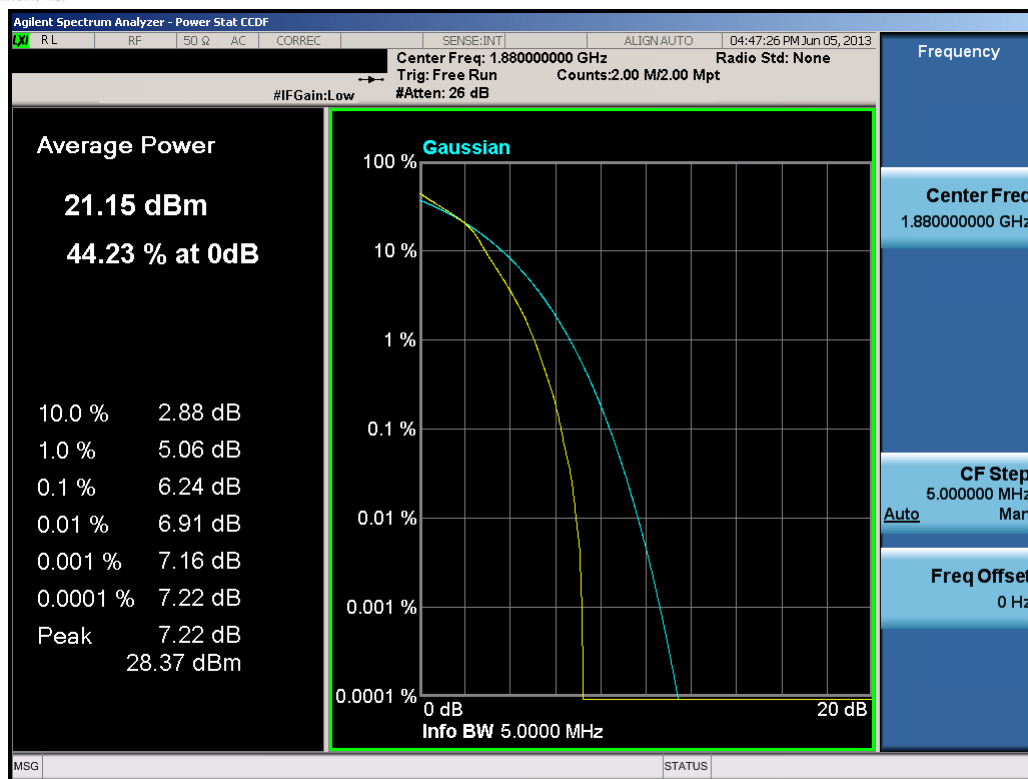


Plot 11-12. Upper Extended Band Edge Plot (5.0MHz QPSK – RB Size 25)



Plot 11-13. PAR Plot (5.0MHz QPSK – RB Size 25)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 109 of 133

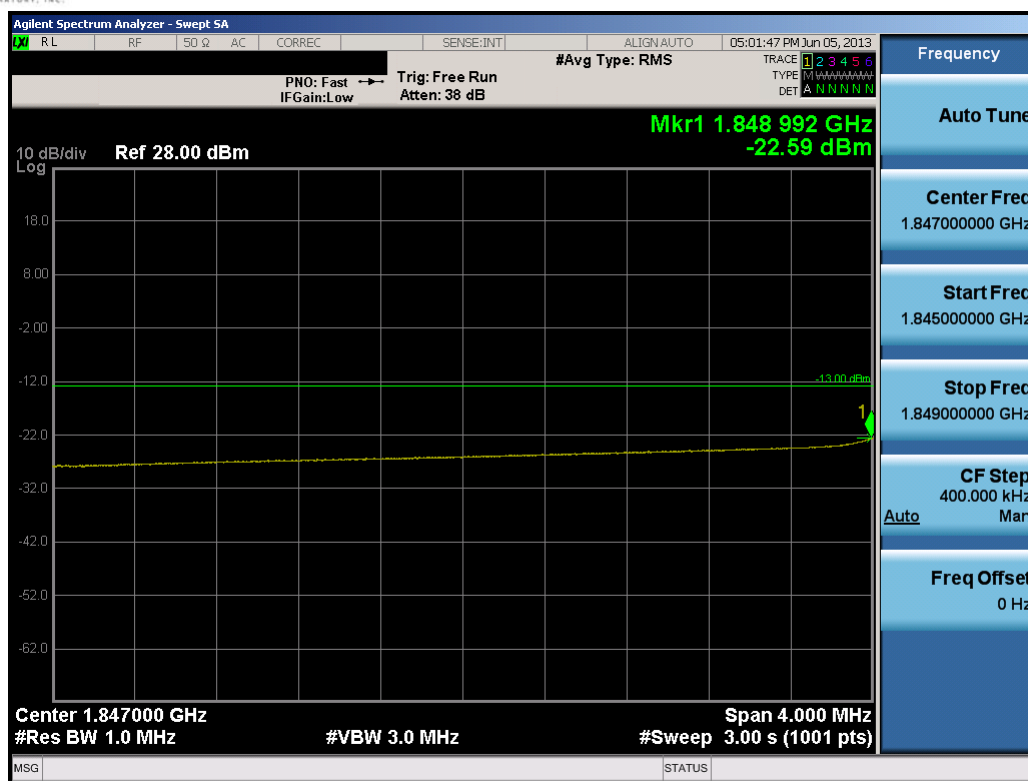


Plot 11-14. PAR Plot (5.0MHz 16-QAM – RB Size 25)

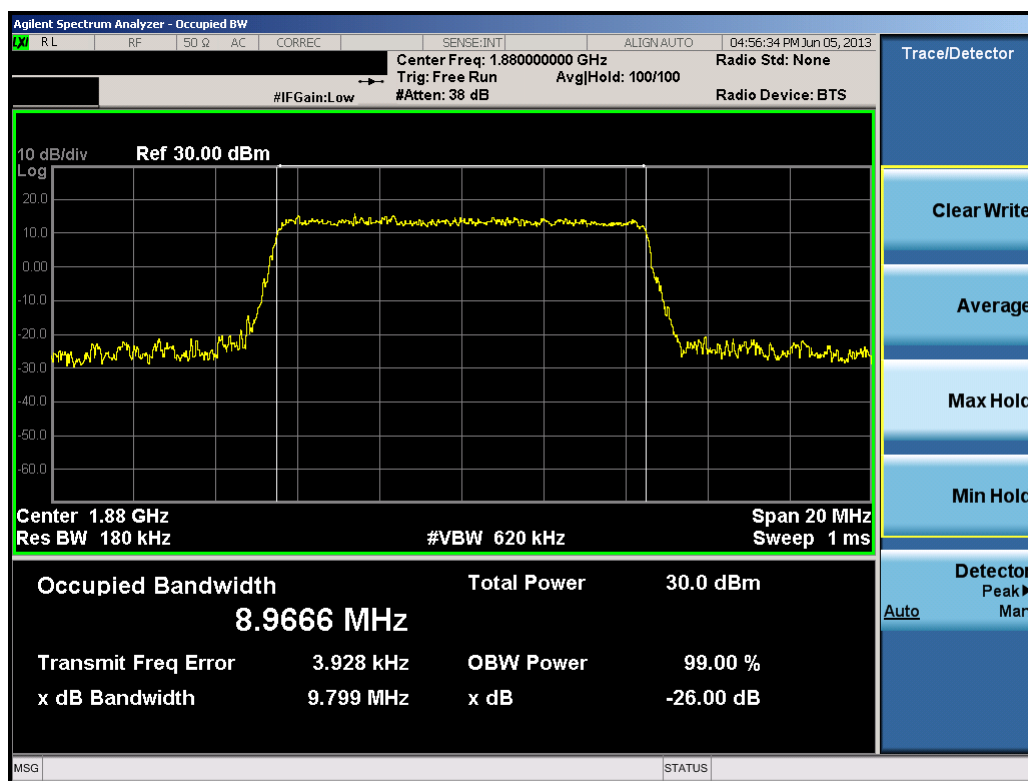


Plot 11-15. Lower Band Edge Plot (10.0MHz QPSK – RB Size 50)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 110 of 133

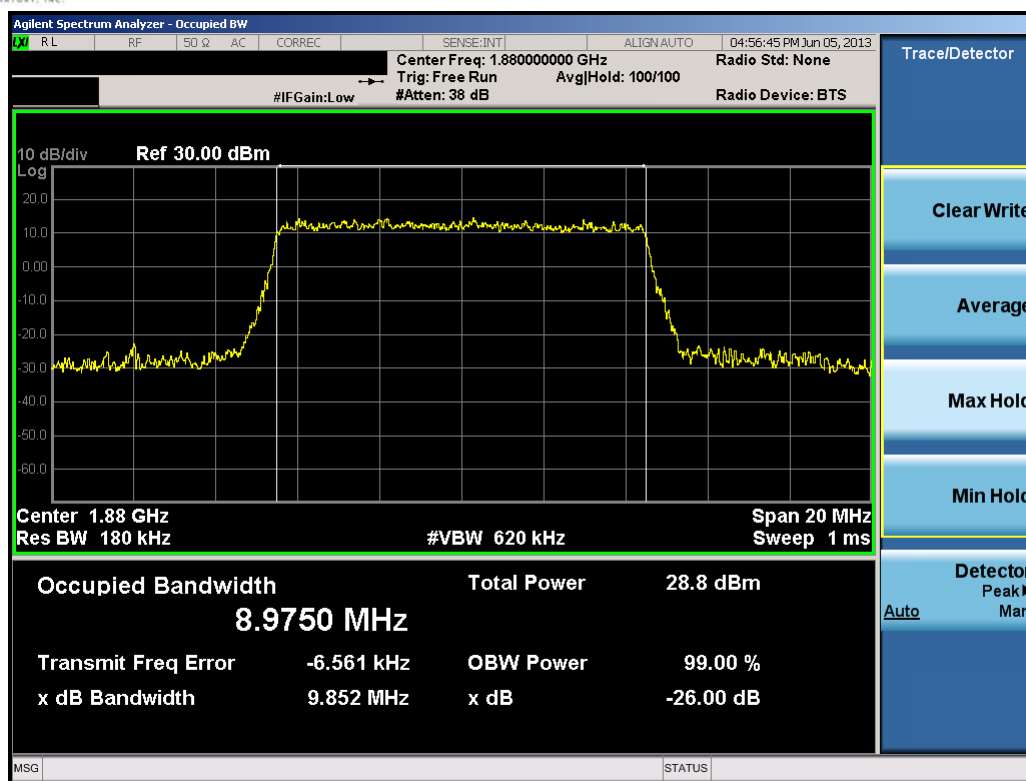


Plot 11-16. Lower Extended Band Edge Plot (10.0MHz QPSK – RB Size 50)

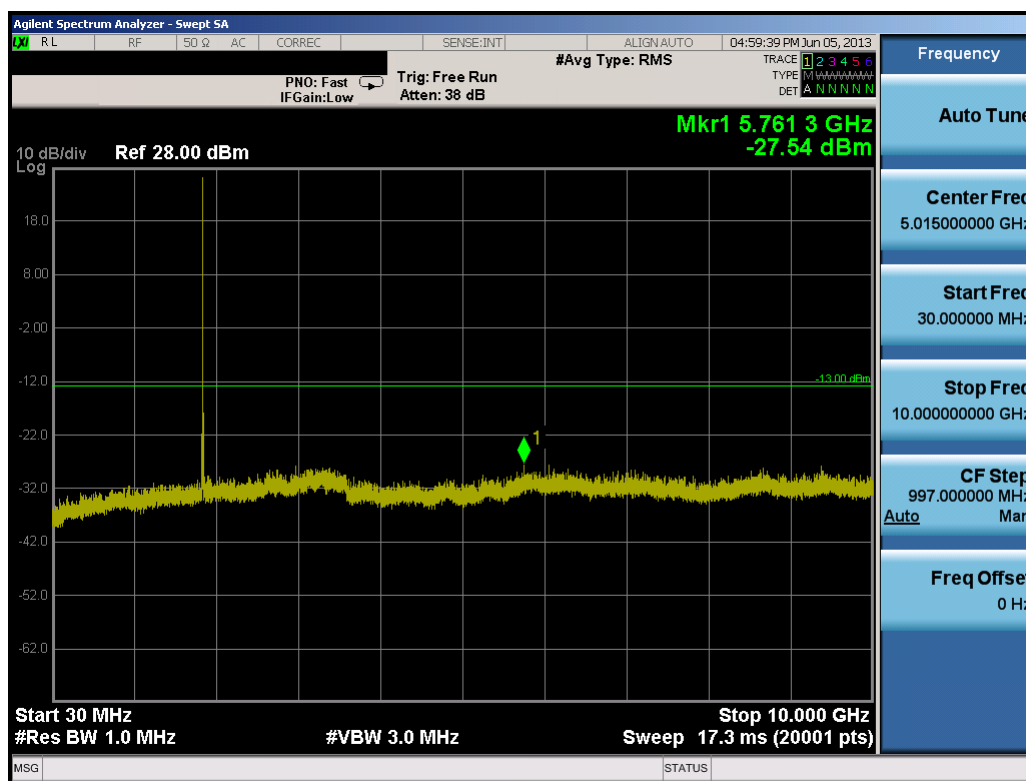


Plot 11-17. Occupied Bandwidth Plot (10.0MHz QPSK – RB Size 50)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 111 of 133

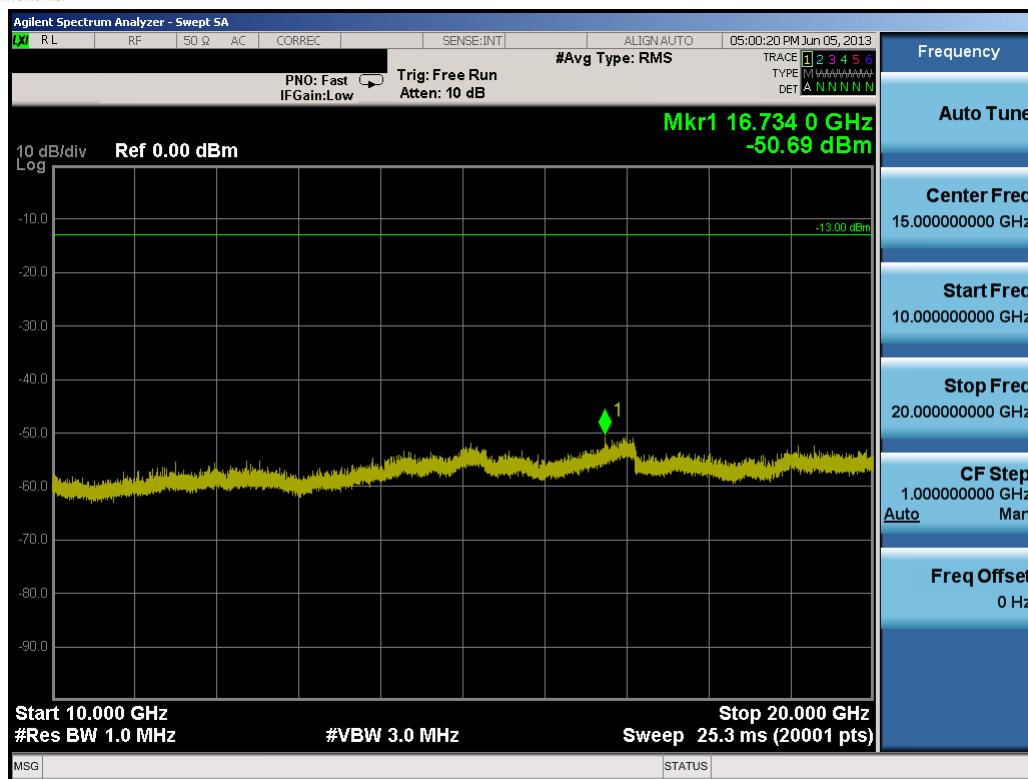


Plot 11-18. Occupied Bandwidth Plot (10.0MHz 16-QAM – RB Size 50)

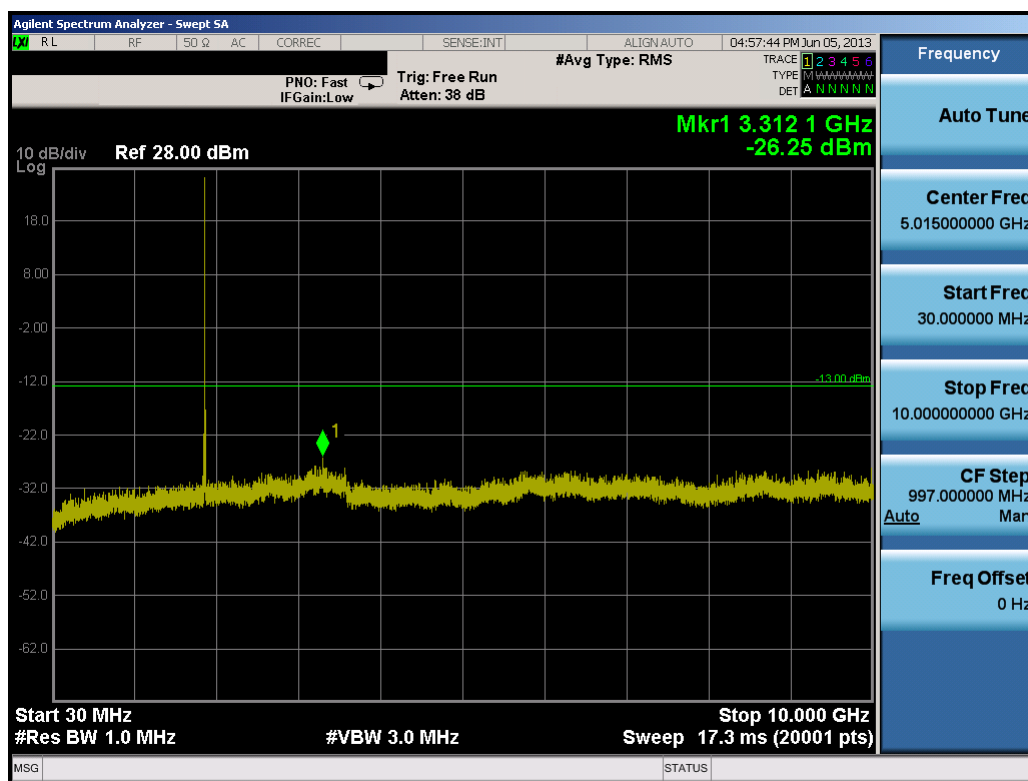


Plot 11-19. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0– Low Channel)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 112 of 133

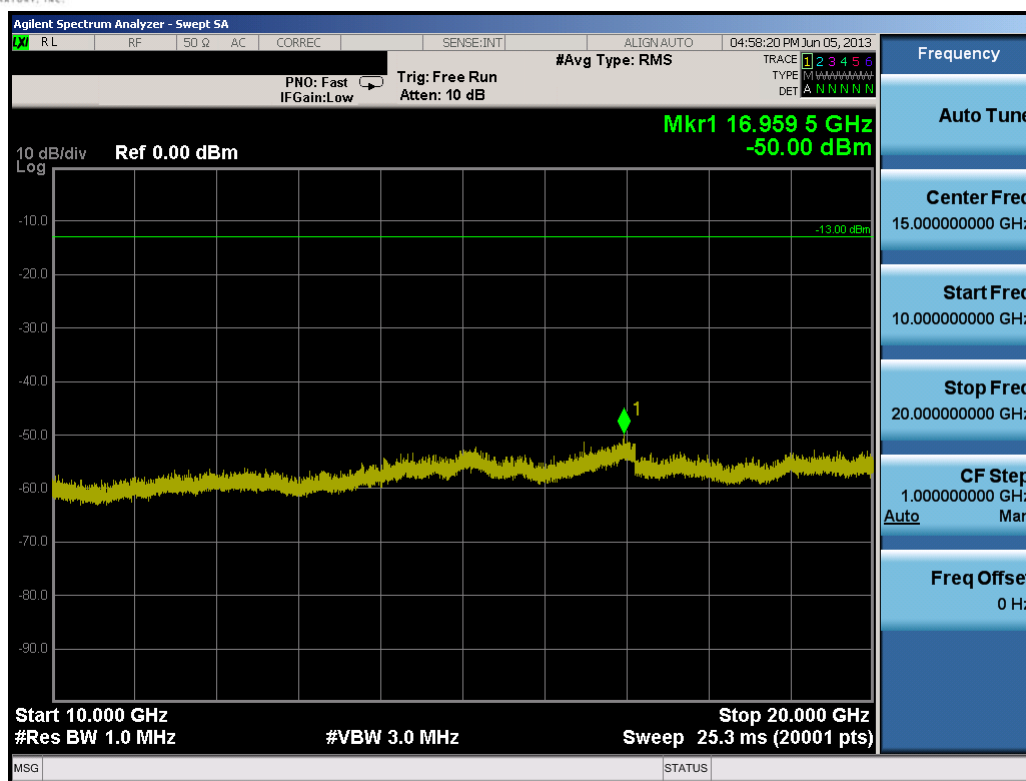


Plot 11-20. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

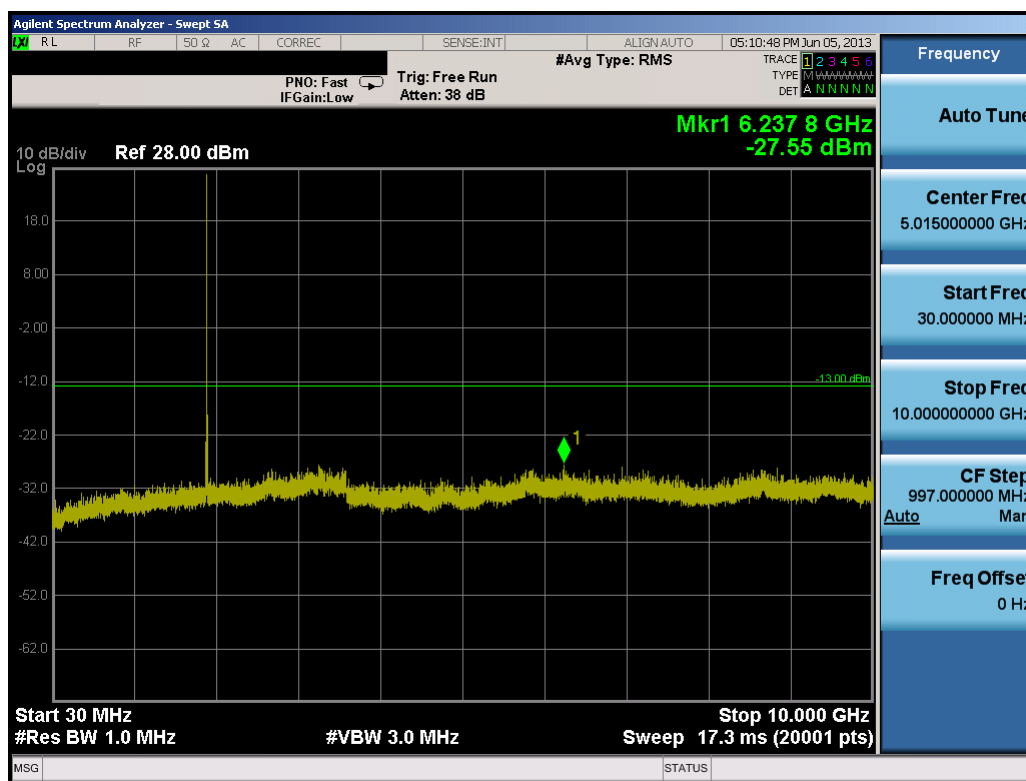


Plot 11-21. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 113 of 133

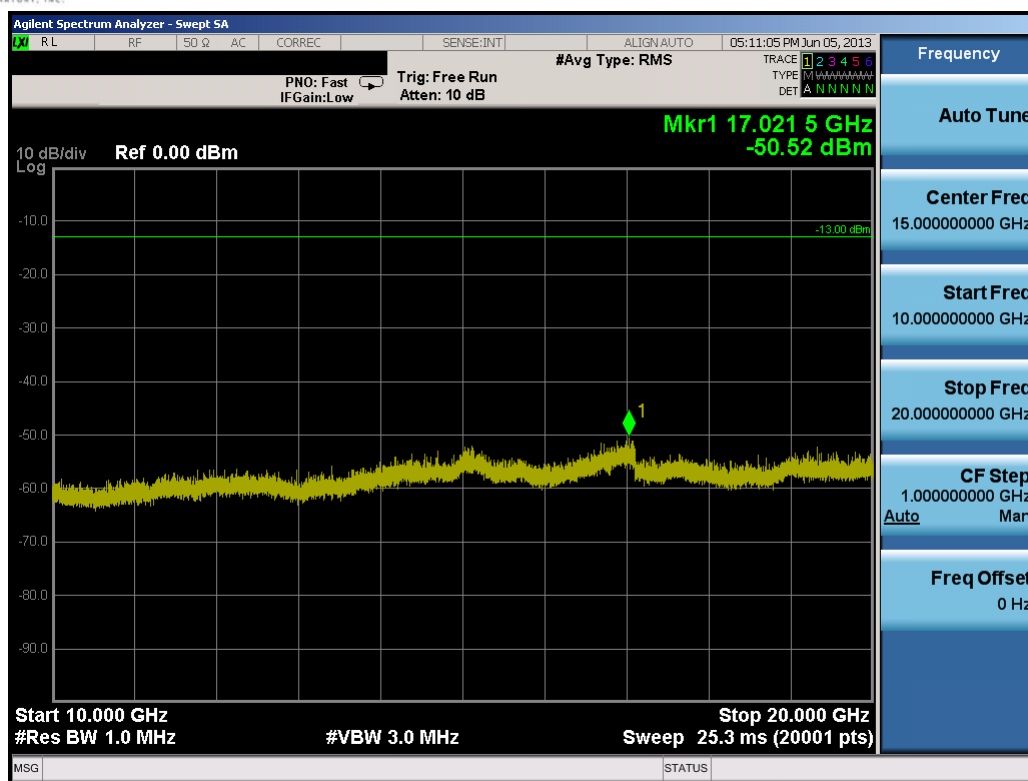


Plot 11-22. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

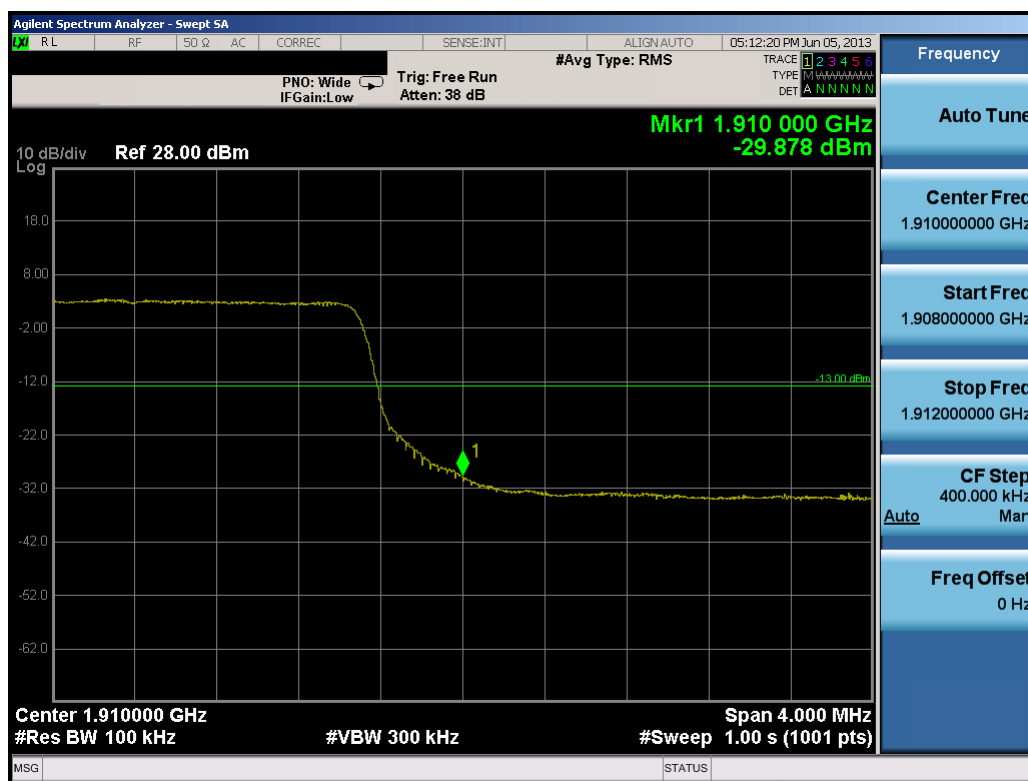


Plot 11-23. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 114 of 133

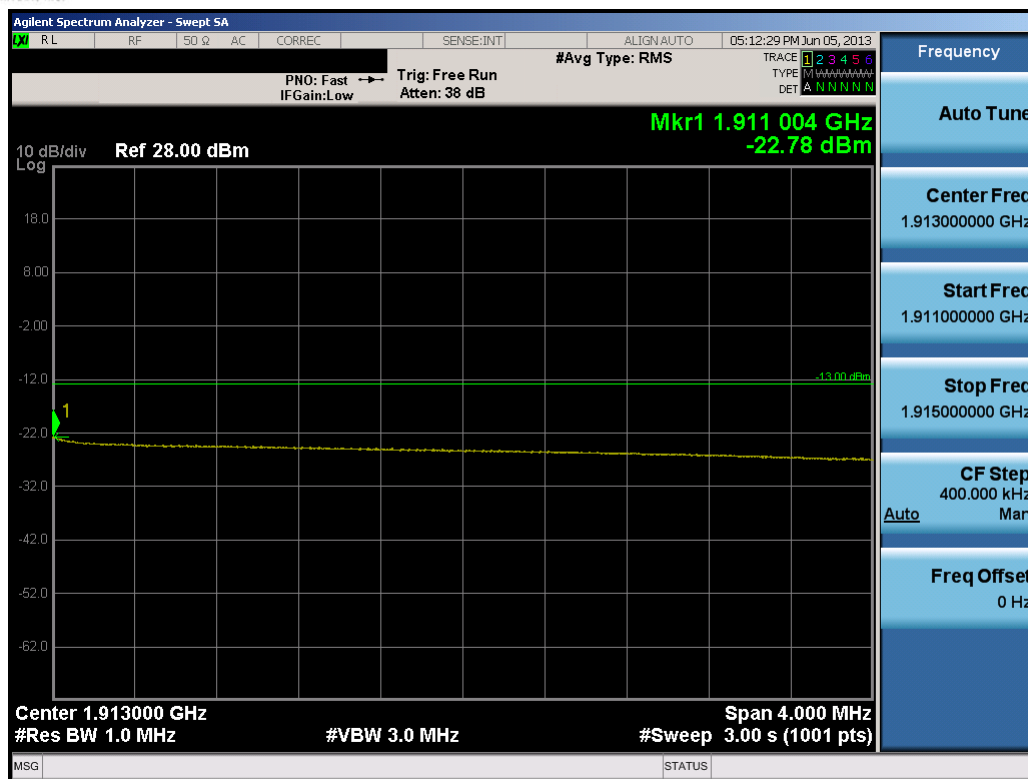


Plot 11-24. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

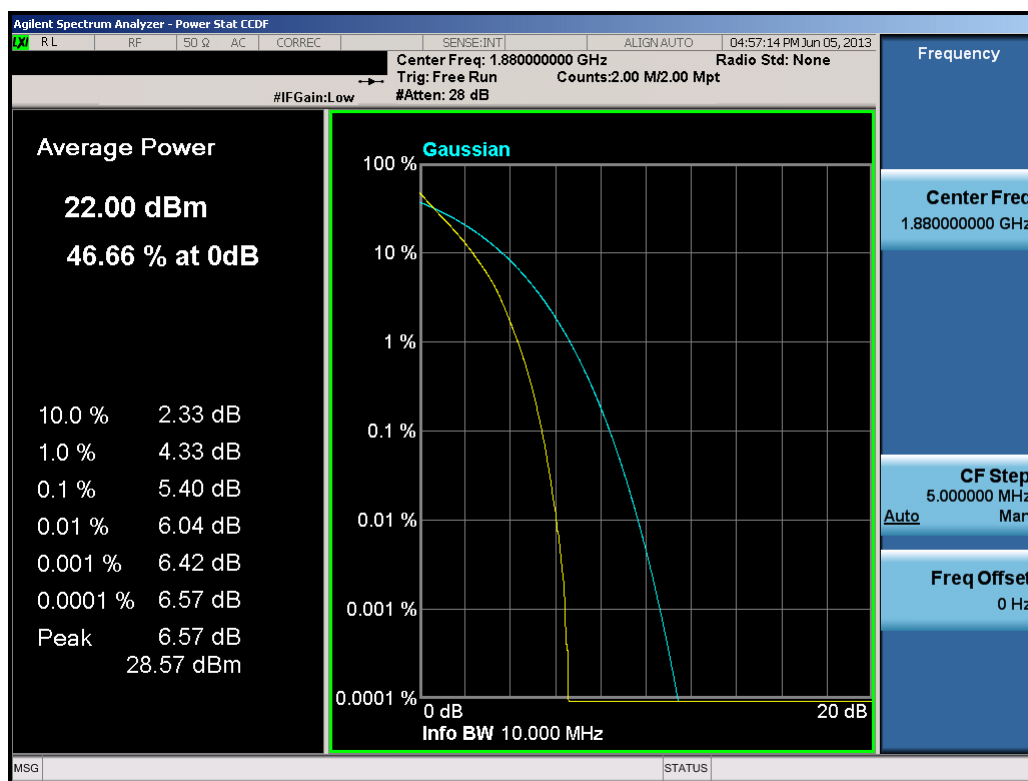


Plot 11-25. Upper Band Edge Plot (10.0MHz QPSK – RB Size 50)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 115 of 133

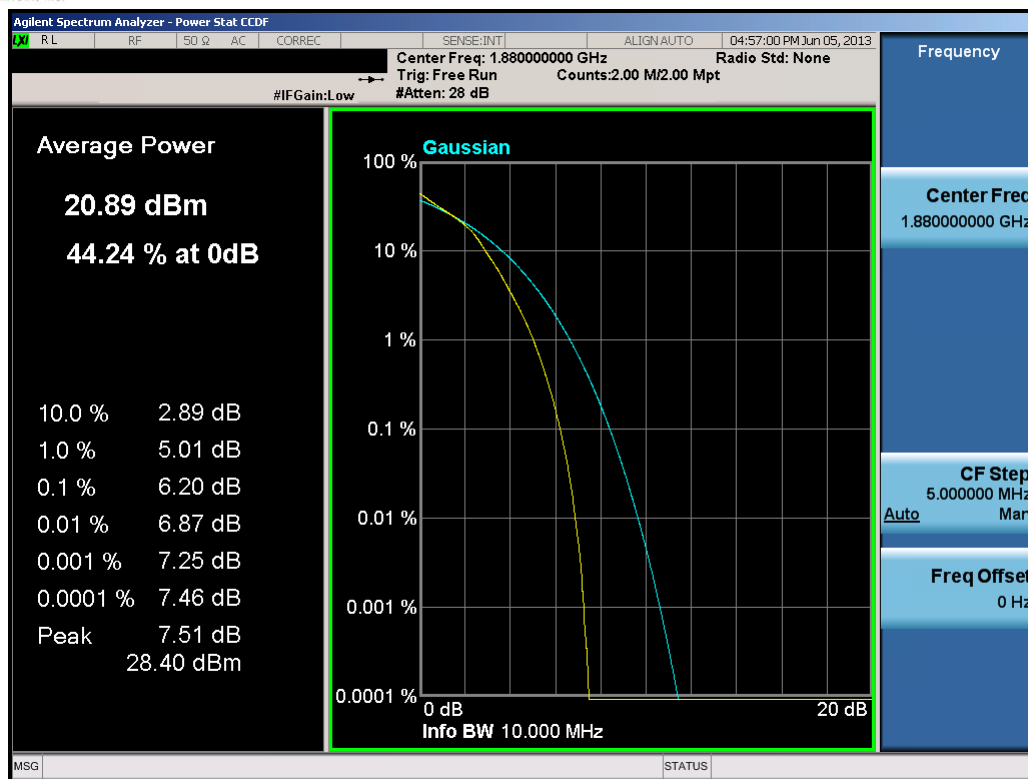


Plot 11-26. Upper Extended Band Edge Plot (10.0MHz QPSK – RB Size 50)



Plot 11-27. PAR Plot (10.0MHz QPSK – RB Size 50)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 116 of 133

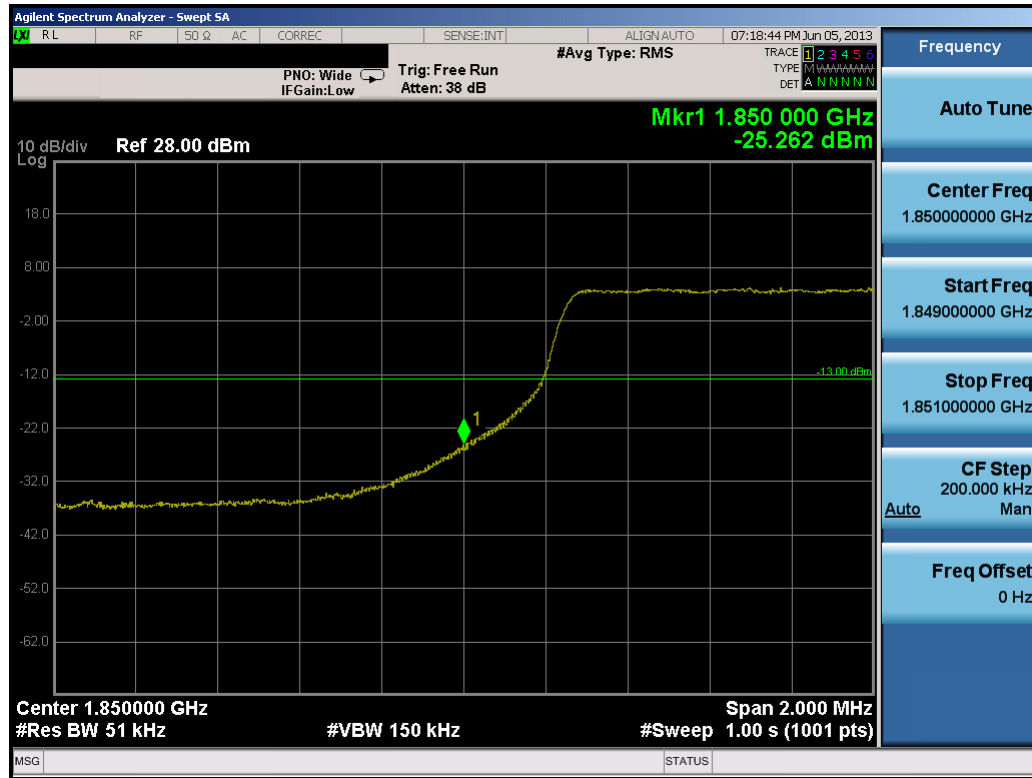


Plot 11-28. PAR Plot (10.0MHz 16-QAM – RB Size 50)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 117 of 133

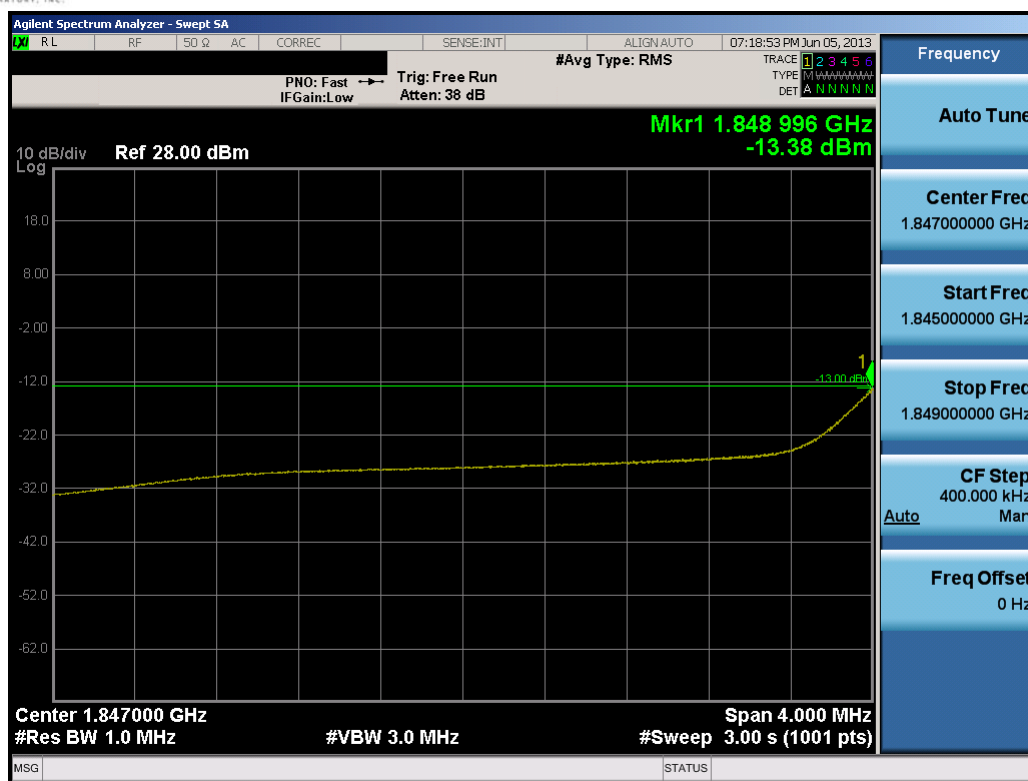
12.0 BAND 25 PLOTS OF EMISSIONS

Note: All bandwidths, RB configurations, and modulations were investigated. The worst case test results are reported below.

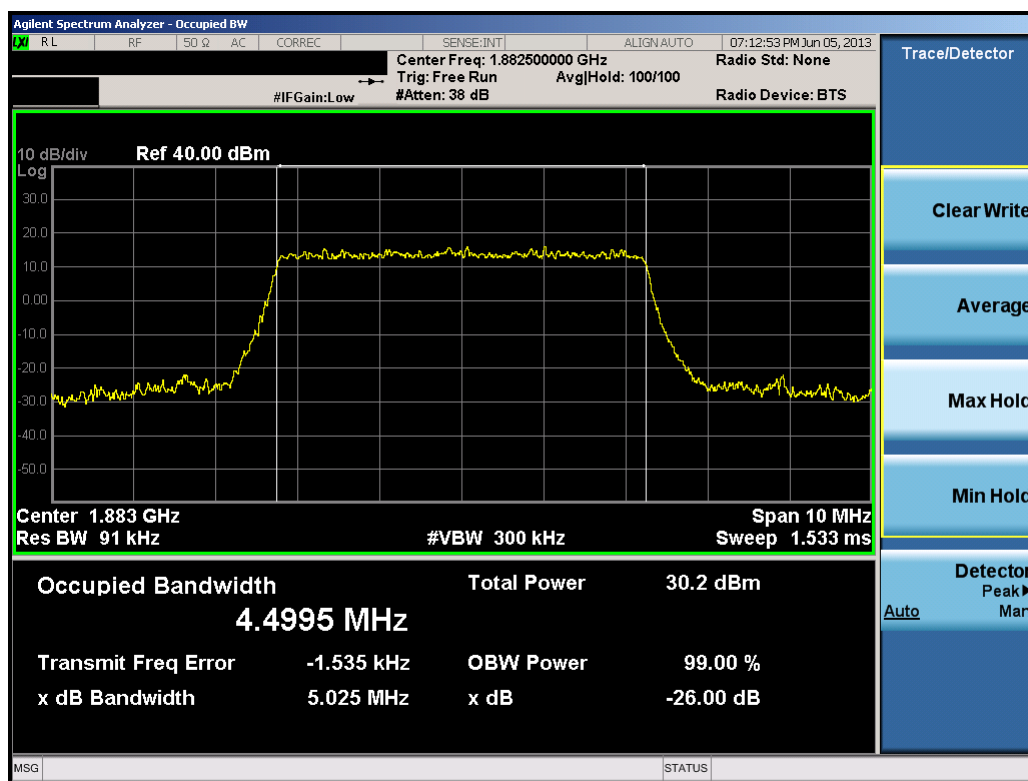


Plot 12-1. Lower Band Edge Plot (5.0MHz QPSK – RB Size 25)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 118 of 133

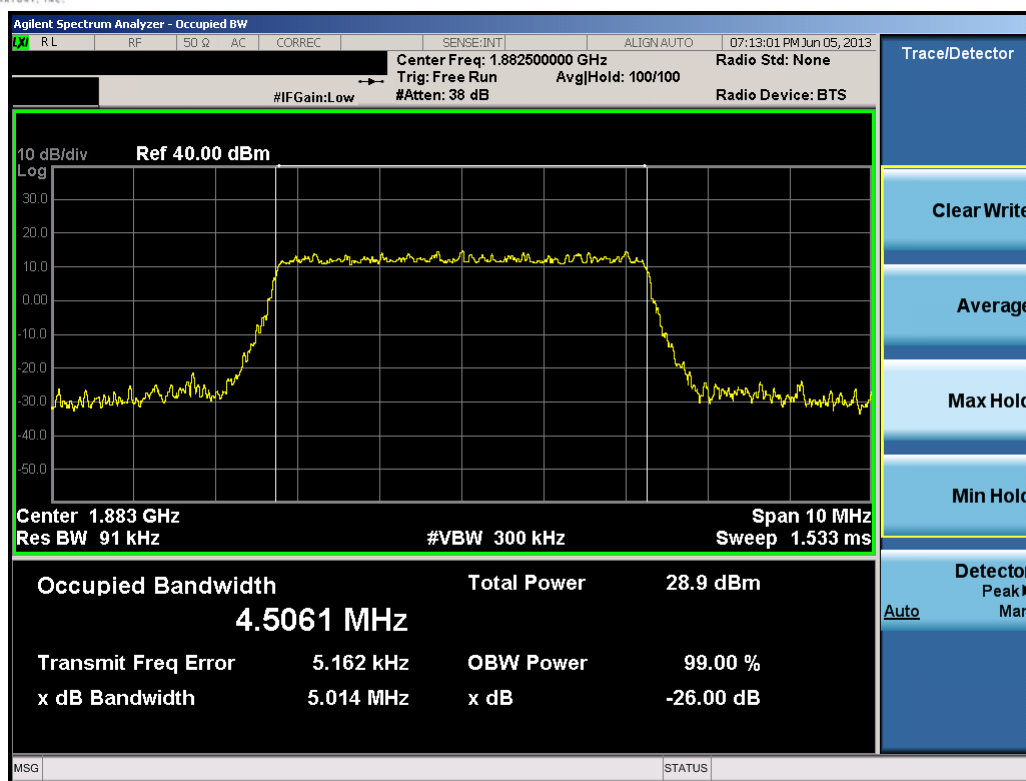


Plot 12-2. Lower Extended Band Edge Plot (5.0MHz QPSK – RB Size 25)

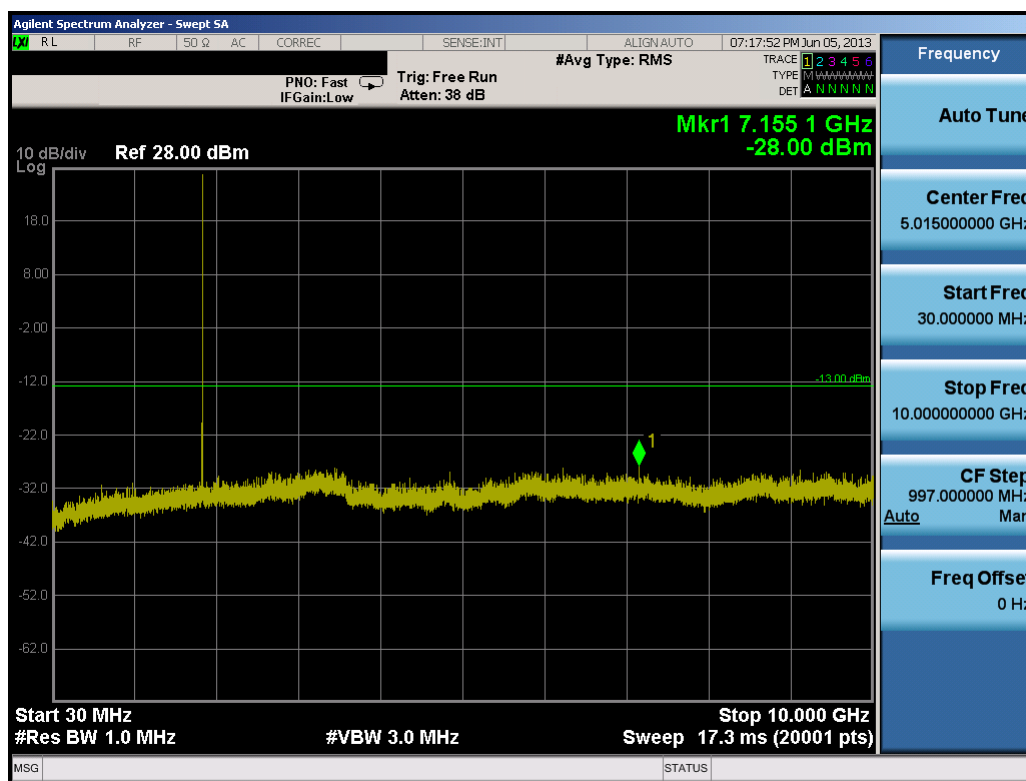


Plot 12-3. Occupied Bandwidth Plot (5.0MHz QPSK – RB Size 25)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 119 of 133

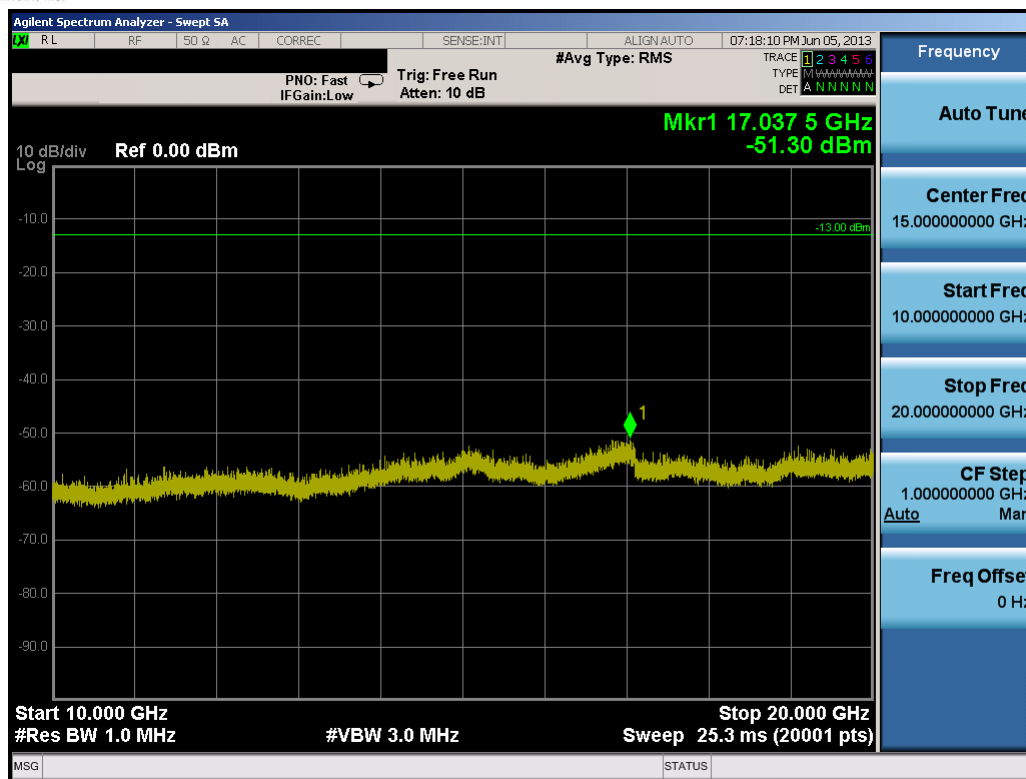


Plot 12-4. Occupied Bandwidth Plot (5.0MHz 16-QAM – RB Size 25)

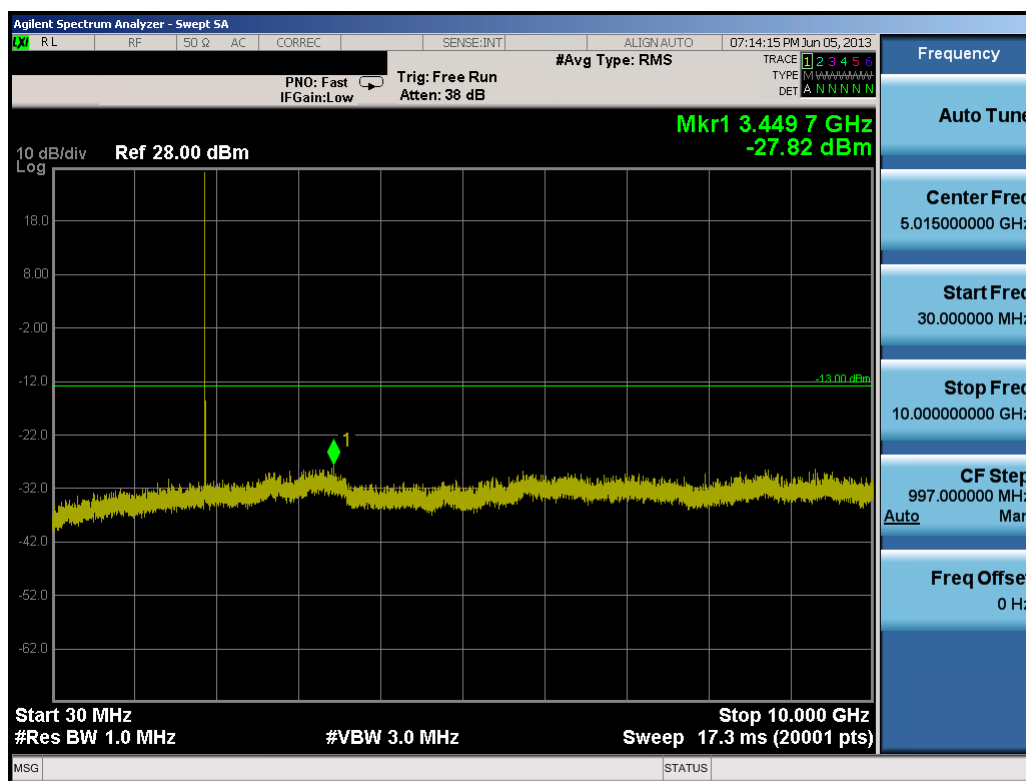


Plot 12-5. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

FCC ID: A3LSCHR960	 FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION) 		Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset	Page 120 of 133

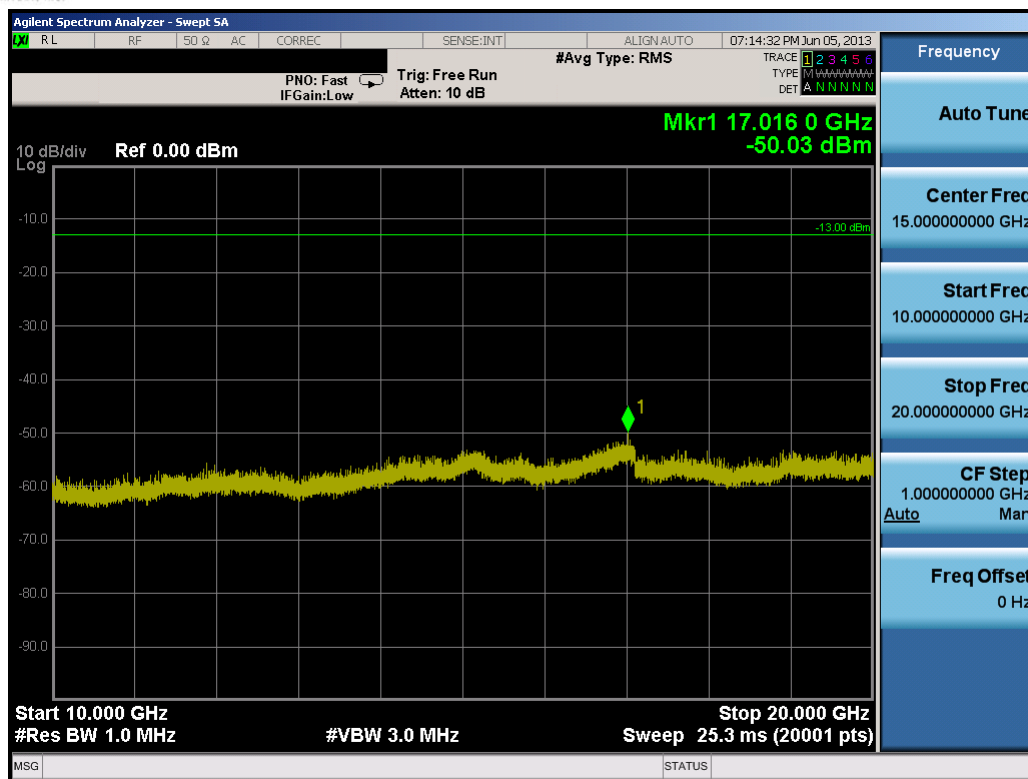


Plot 12-6. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

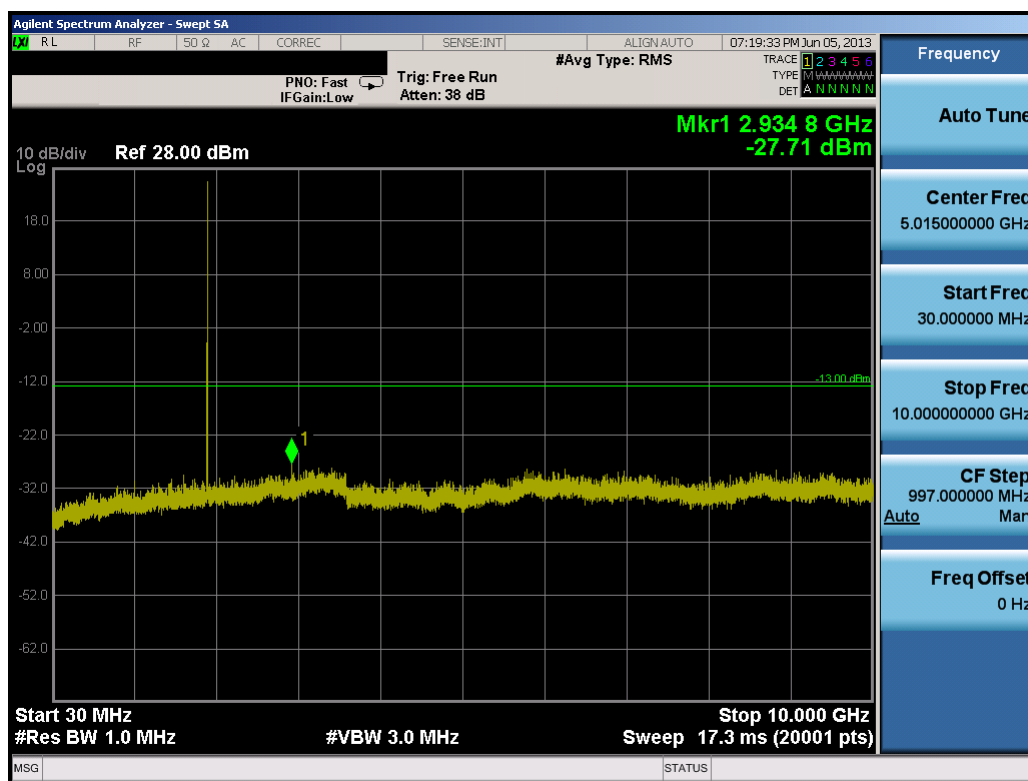


Plot 12-7. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSCHR960	 FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION) 		Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset	Page 121 of 133

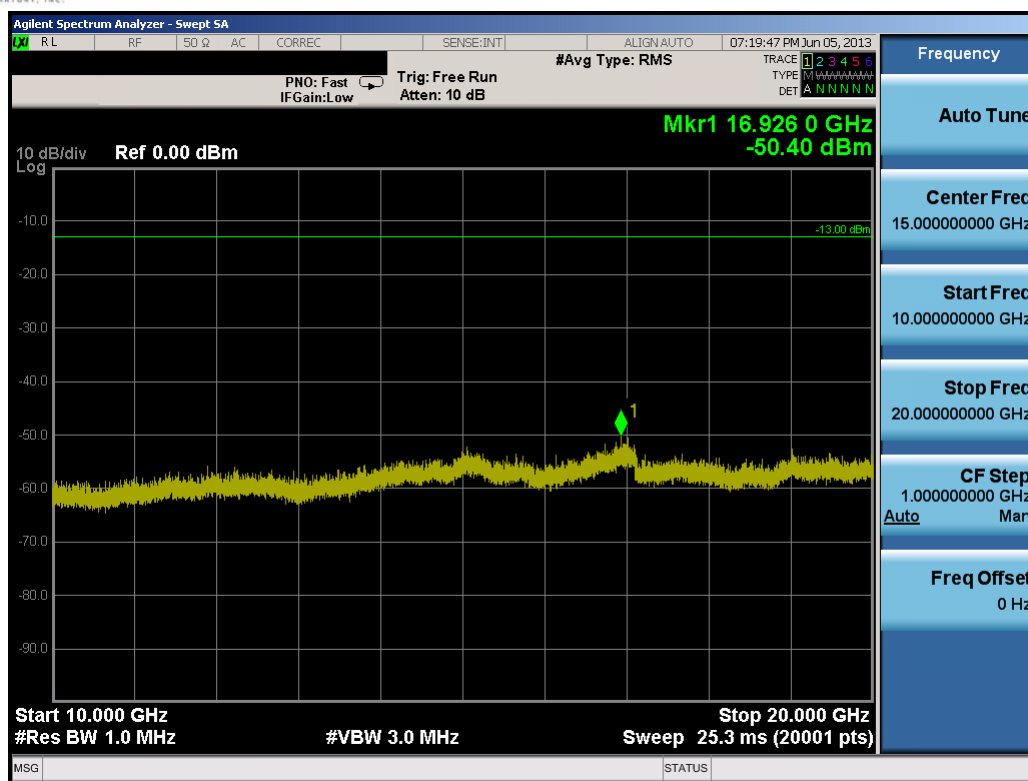


Plot 12-8. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

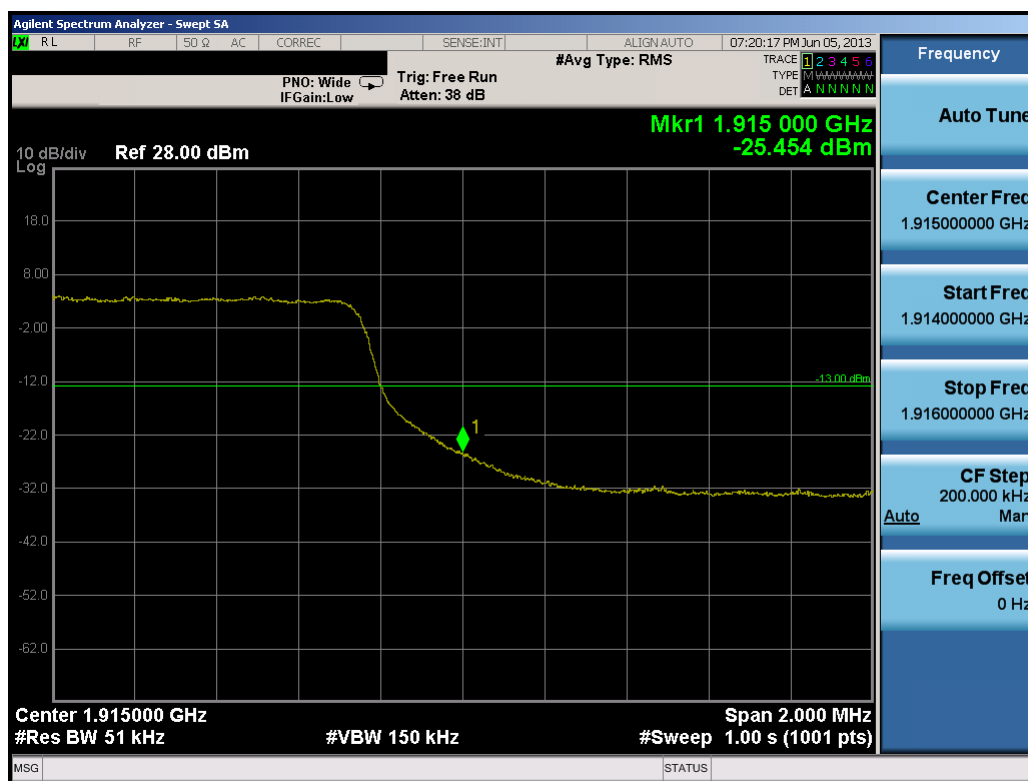


Plot 12-9. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 122 of 133



Plot 12-10. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

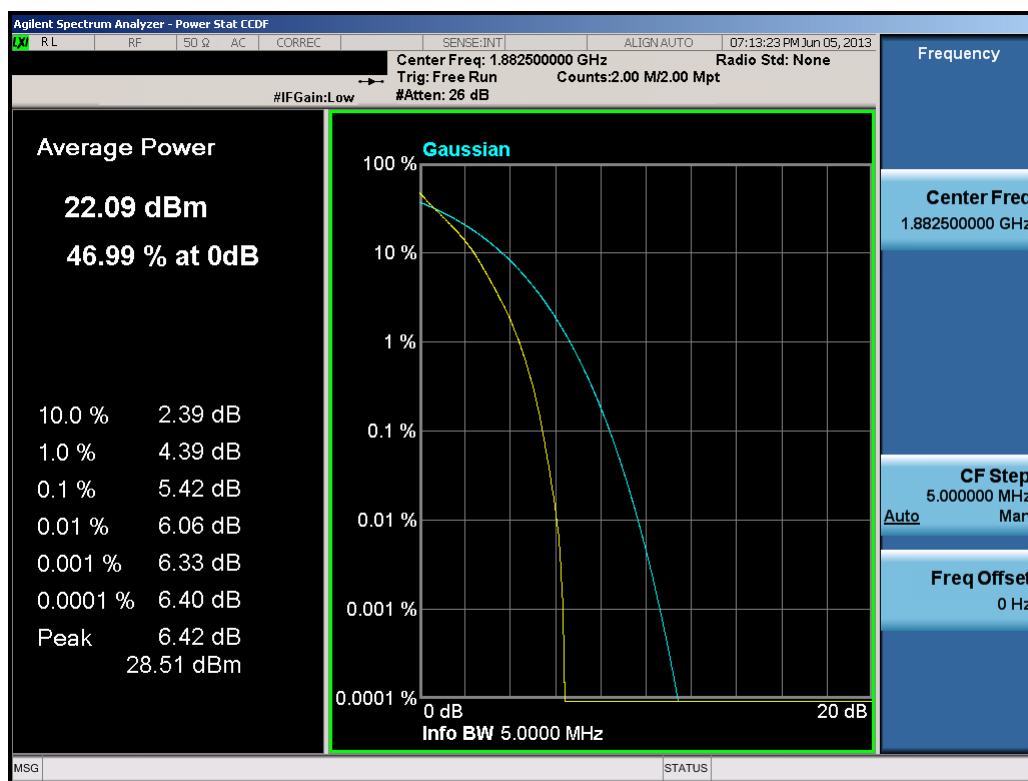


Plot 12-11. Upper Band Edge Plot (5.0MHz QPSK – RB Size 25)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 123 of 133

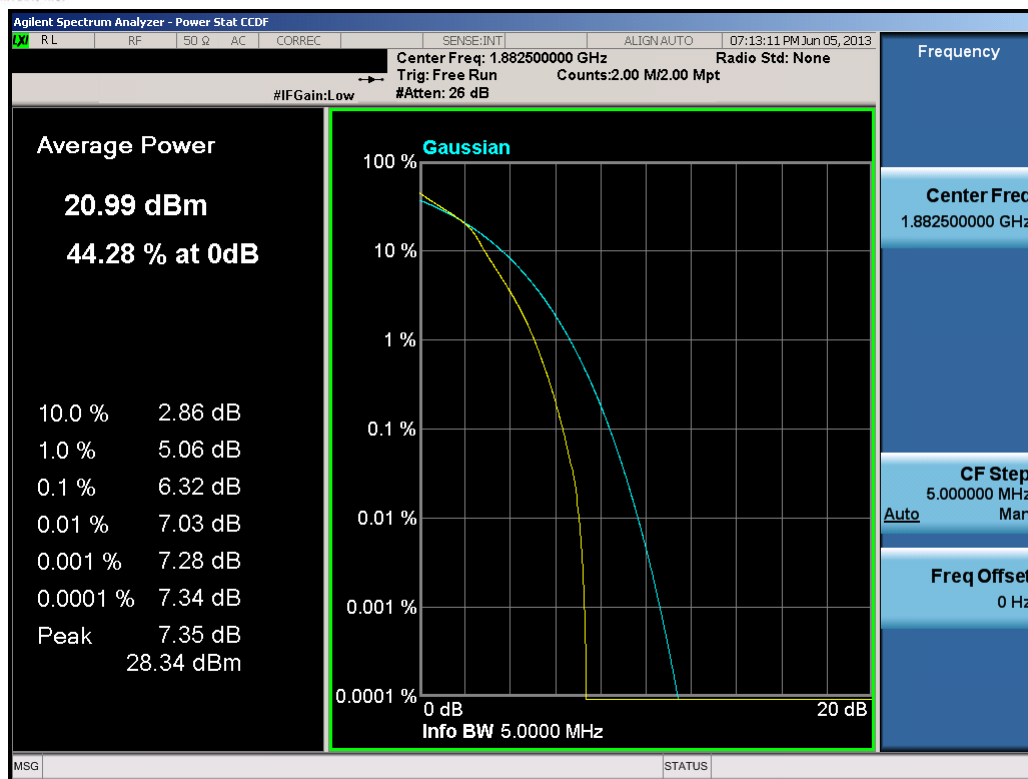


Plot 12-12. Upper Extended Band Edge Plot (5.0MHz QPSK – RB Size 25)

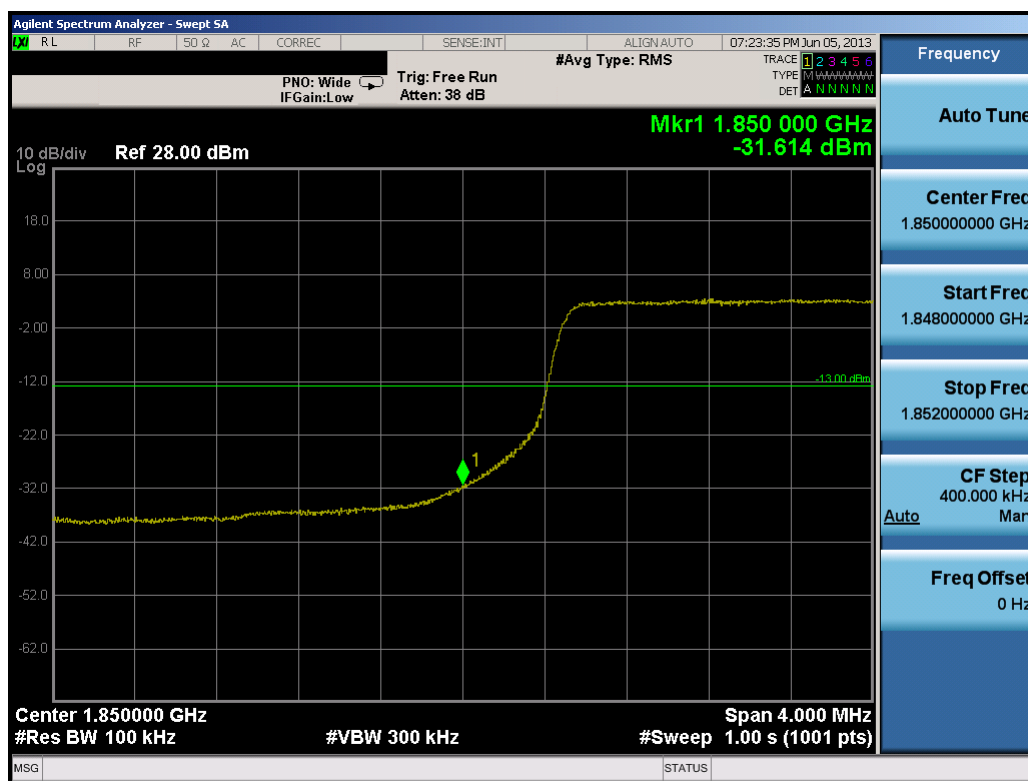


Plot 12-13. PAR Plot (5.0MHz QPSK – RB Size 25)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 124 of 133

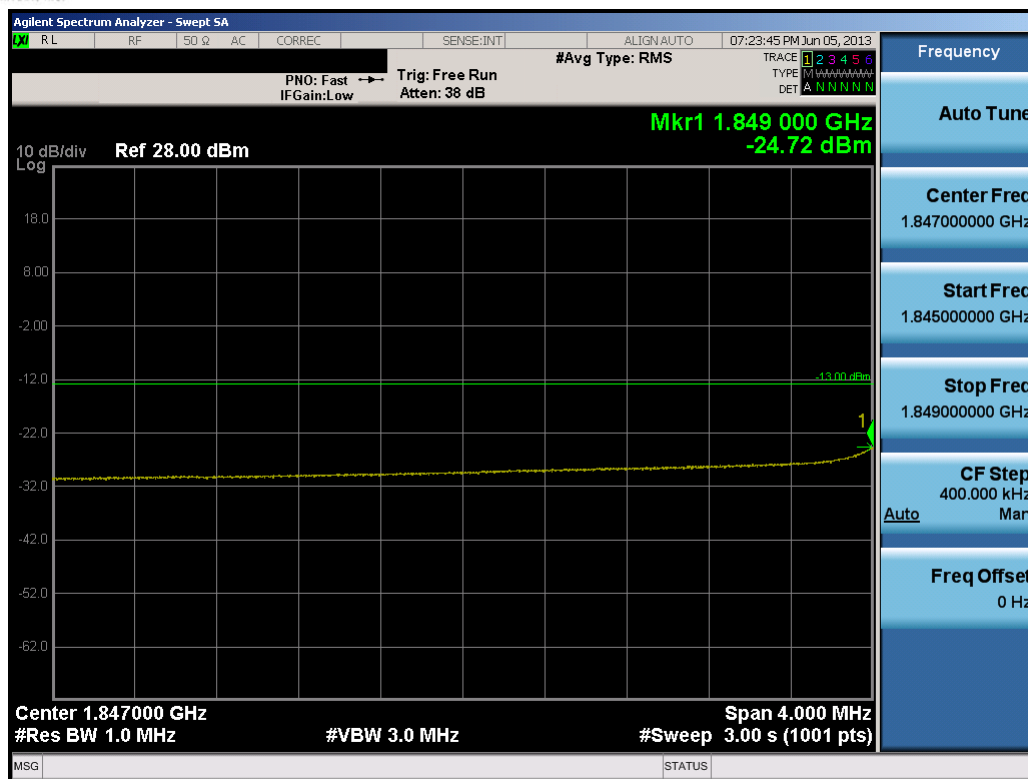


Plot 12-14. PAR Plot (5.0MHz 16-QAM – RB Size 25)

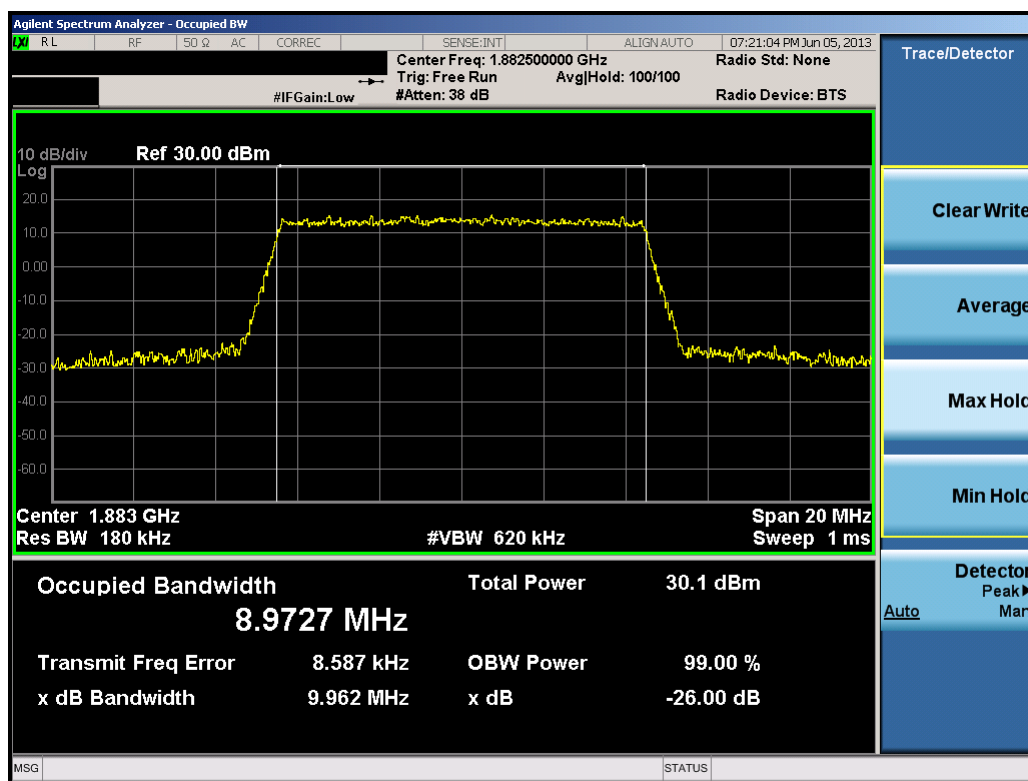


Plot 12-15. Lower Band Edge Plot (10.0MHz QPSK – RB Size 50)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 125 of 133

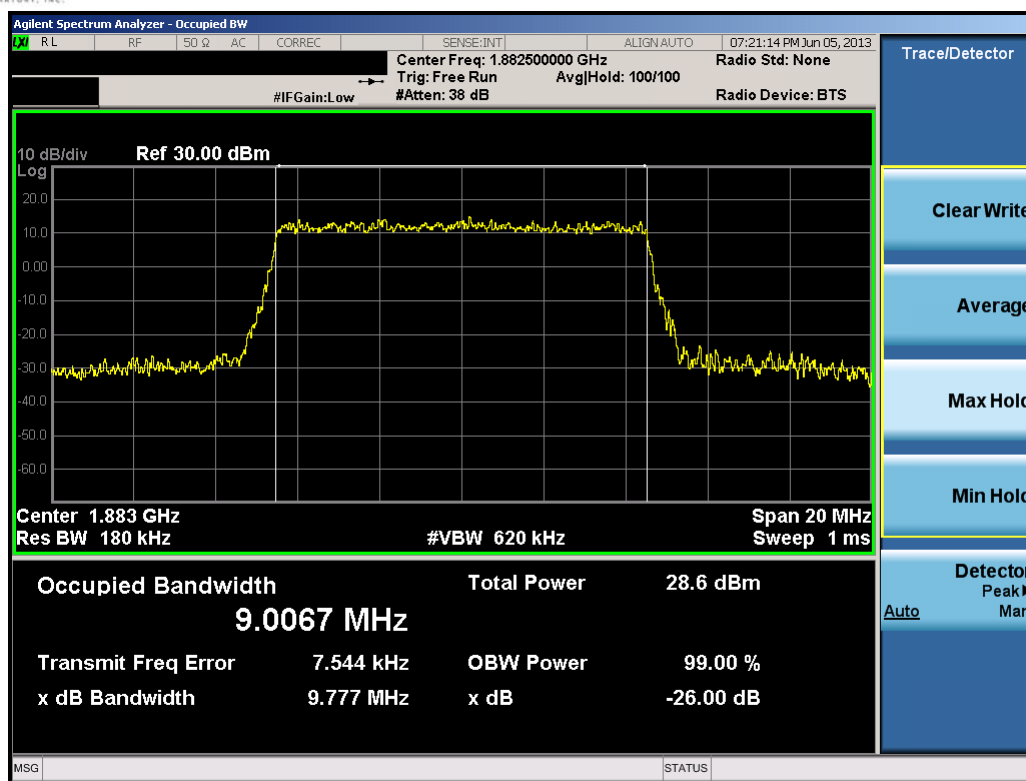


Plot 12-16. Lower Extended Band Edge Plot (10.0MHz QPSK – RB Size 50)

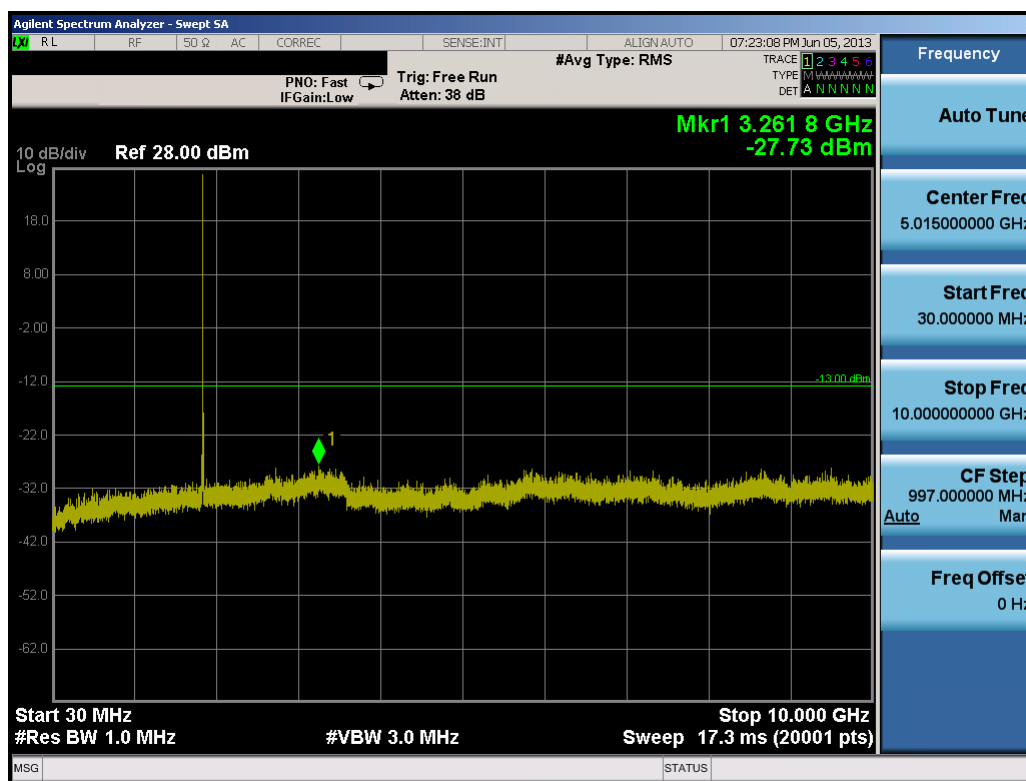


Plot 12-17. Occupied Bandwidth Plot (10.0MHz QPSK – RB Size 50)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 126 of 133

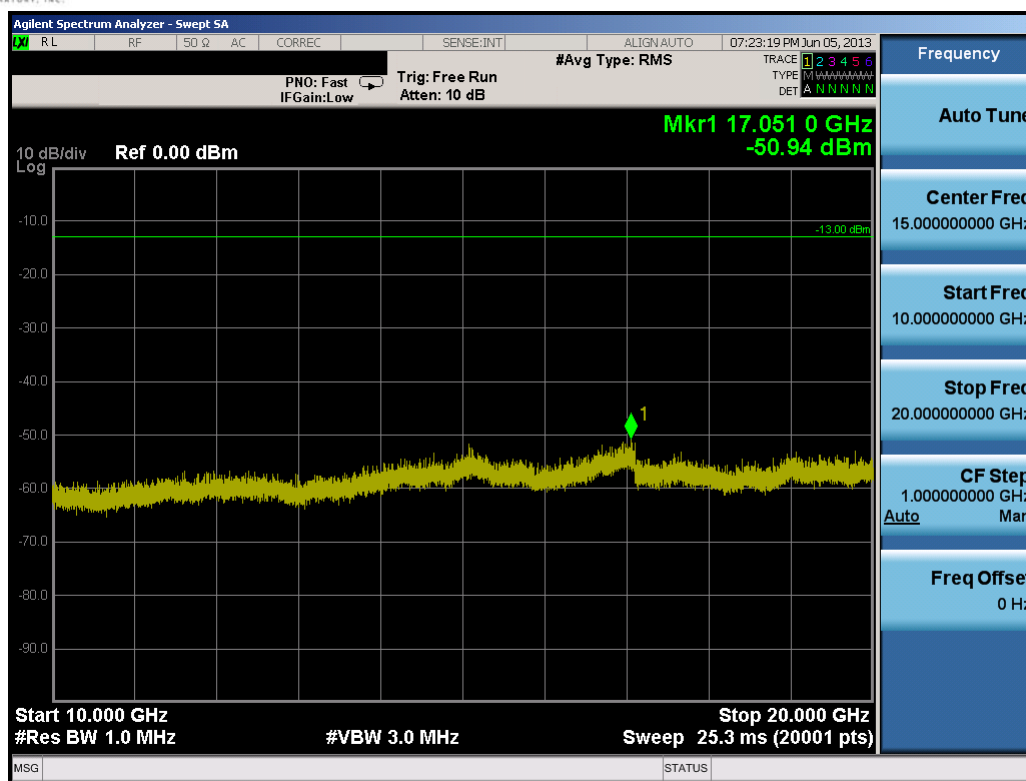


Plot 12-18. Occupied Bandwidth Plot (10.0MHz 16-QAM – RB Size 50)

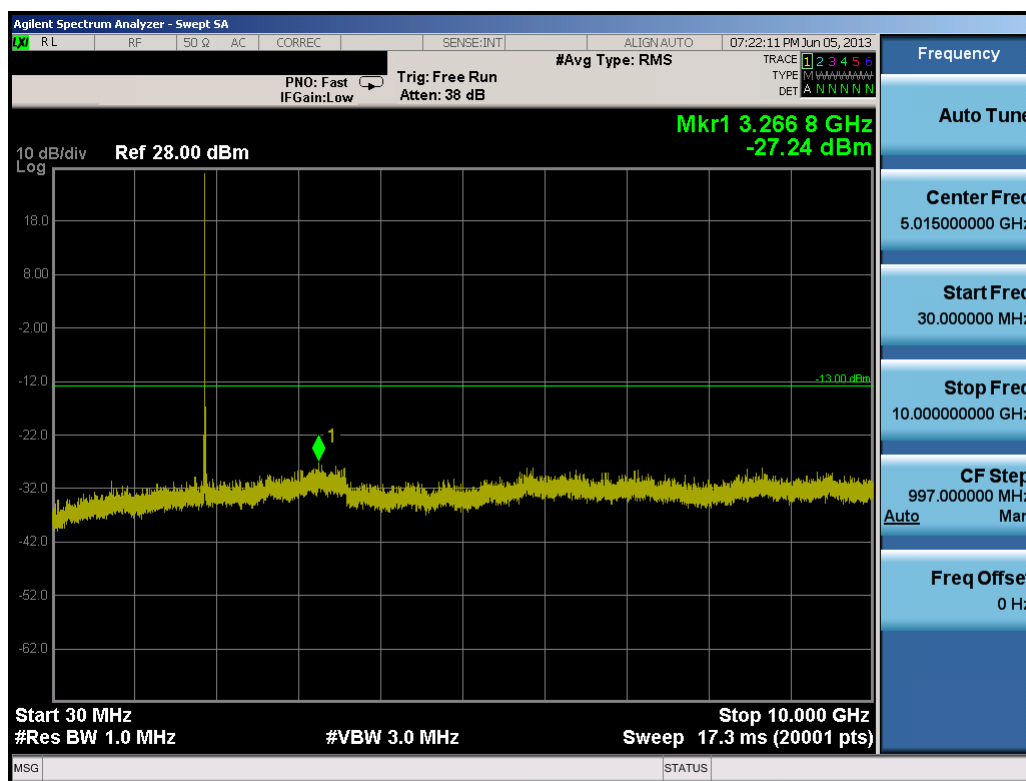


Plot 12-19. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0– Low Channel)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 127 of 133

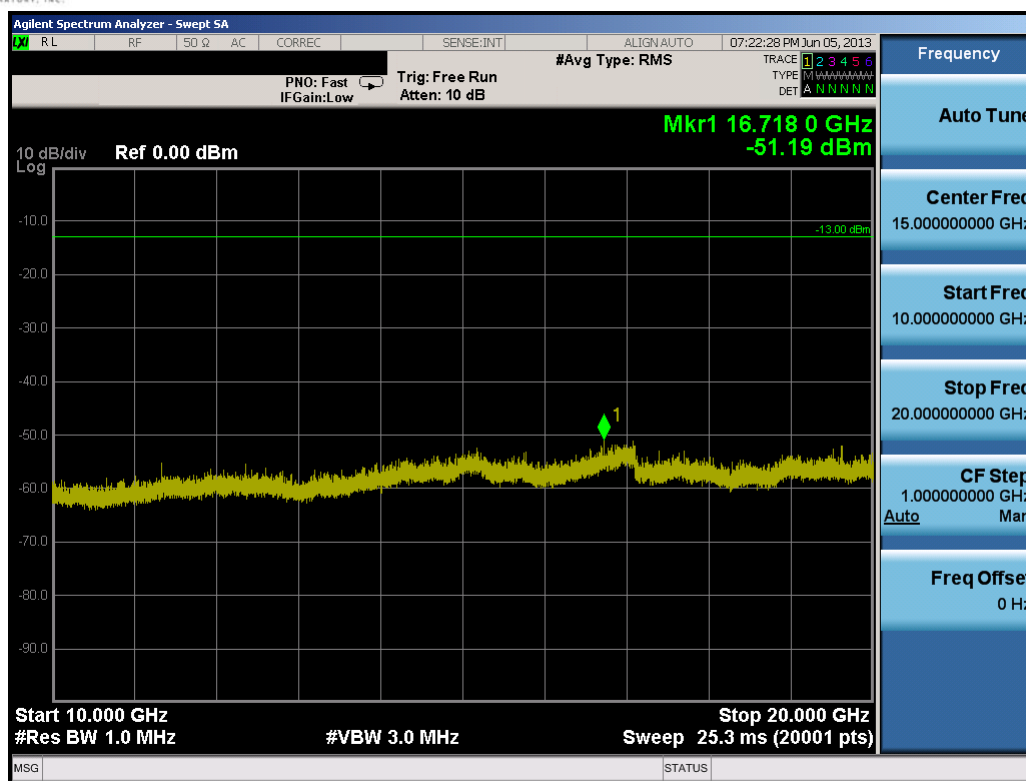


Plot 12-20. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

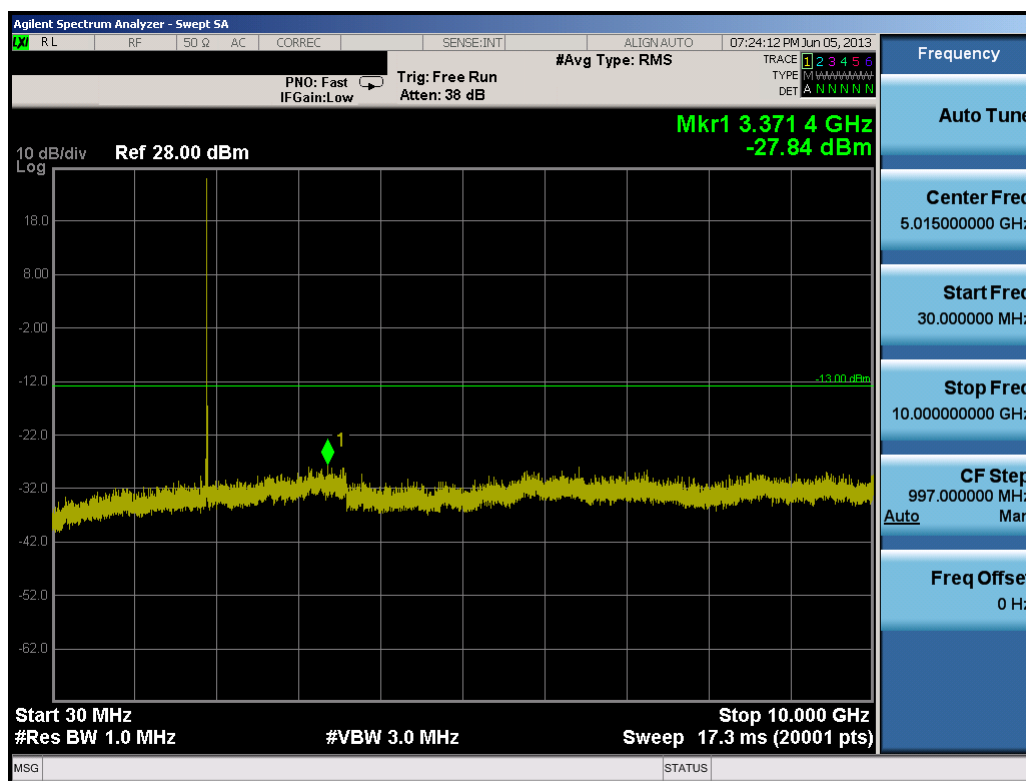


Plot 12-21. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 128 of 133

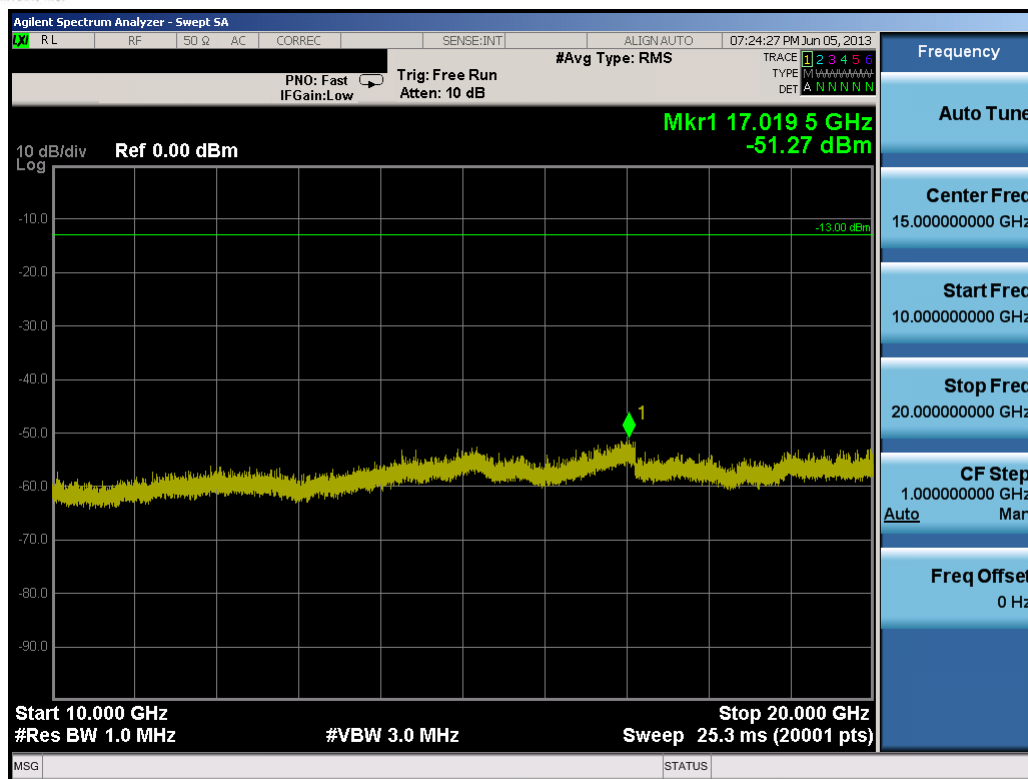


Plot 12-22. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 12-23. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 129 of 133

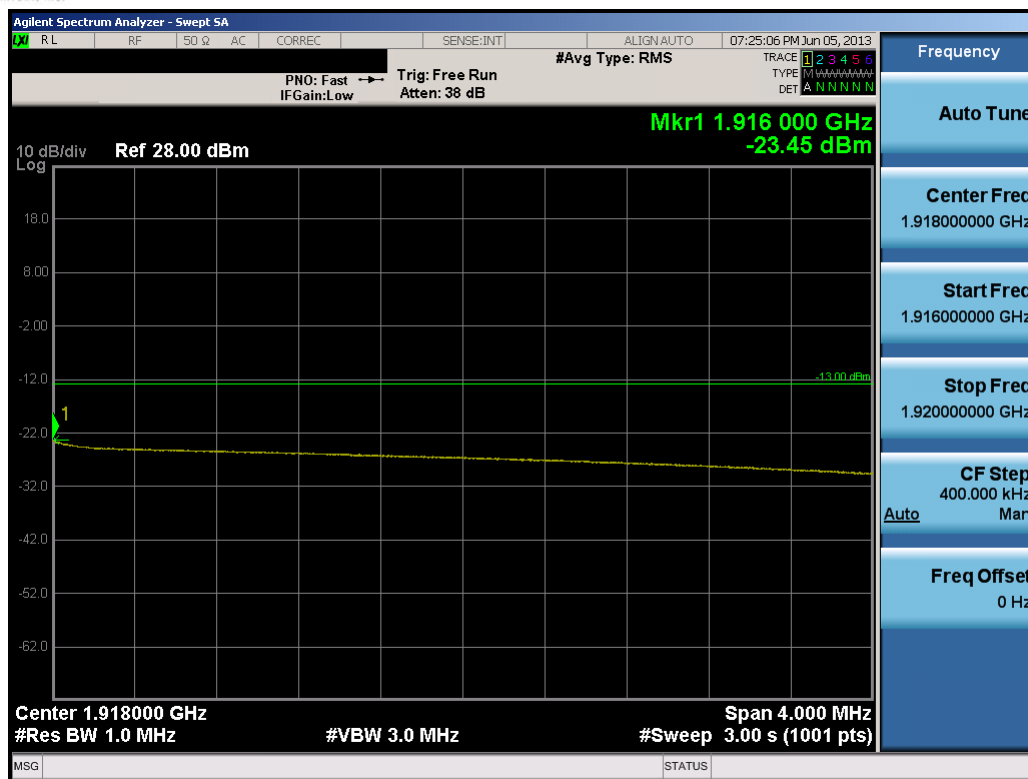


Plot 12-24. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

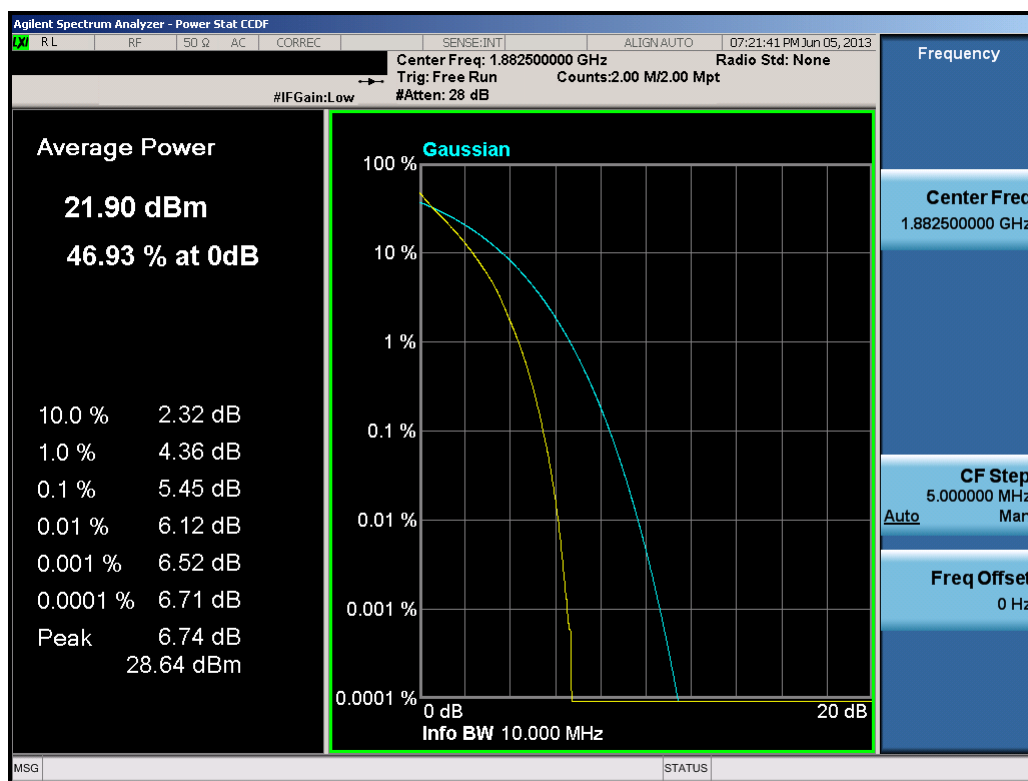


Plot 12-25. Upper Band Edge Plot (10.0MHz QPSK – RB Size 50)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 130 of 133

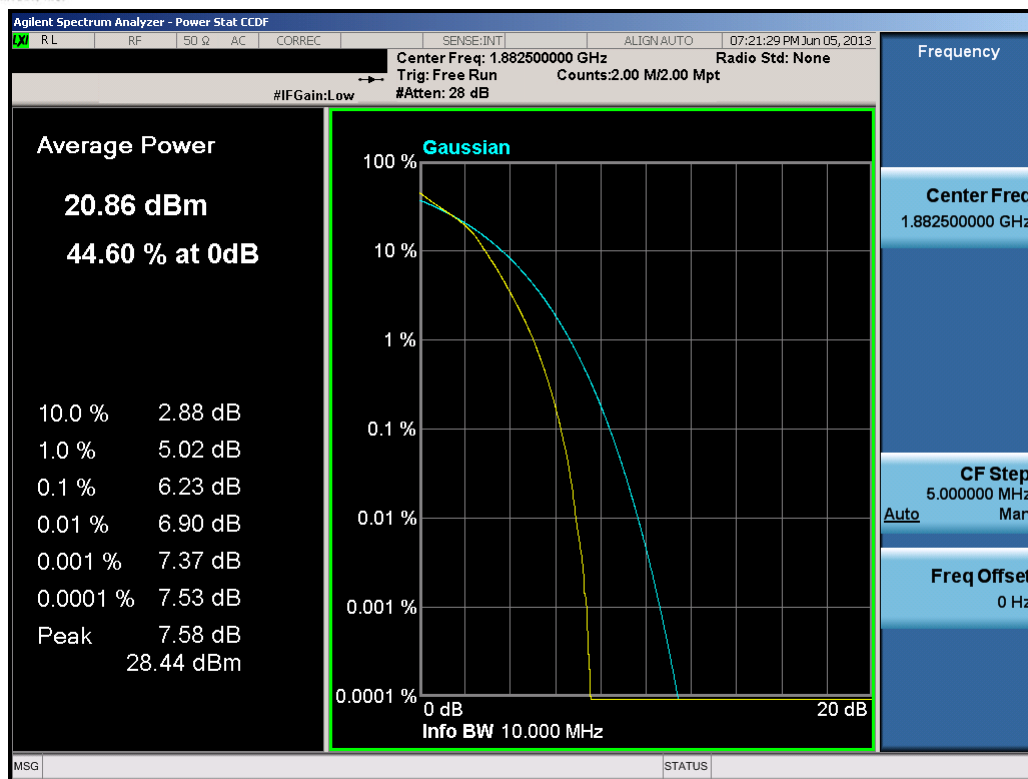


Plot 12-26. Upper Extended Band Edge Plot (10.0MHz QPSK – RB Size 50)



Plot 12-27. PAR Plot (10.0MHz QPSK – RB Size 50)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 131 of 133



Plot 12-28. PAR Plot (10.0MHz 16-QAM - RB Size 50)

FCC ID: A3LSCHR960	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 132 of 133

13.0 CONCLUSION

The data collected relate only to the item(s) tested and show that the **Samsung Portable Handset FCC ID: A3LSCHR960** complies with all the requirements of Parts 2, 22, 24, 27 of the FCC rules for LTE operation only.

FCC ID: A3LSCHR960		FCC Pt. 22, 24, & 27 LTE MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1306030939.A3L	Test Dates: 06/05 - 07/09/2013	EUT Type: Portable Handset		Page 133 of 133